

Nexperia Image Classification II

WITH CONVOLUTION NEURON NETWORK
WONG WING KIN



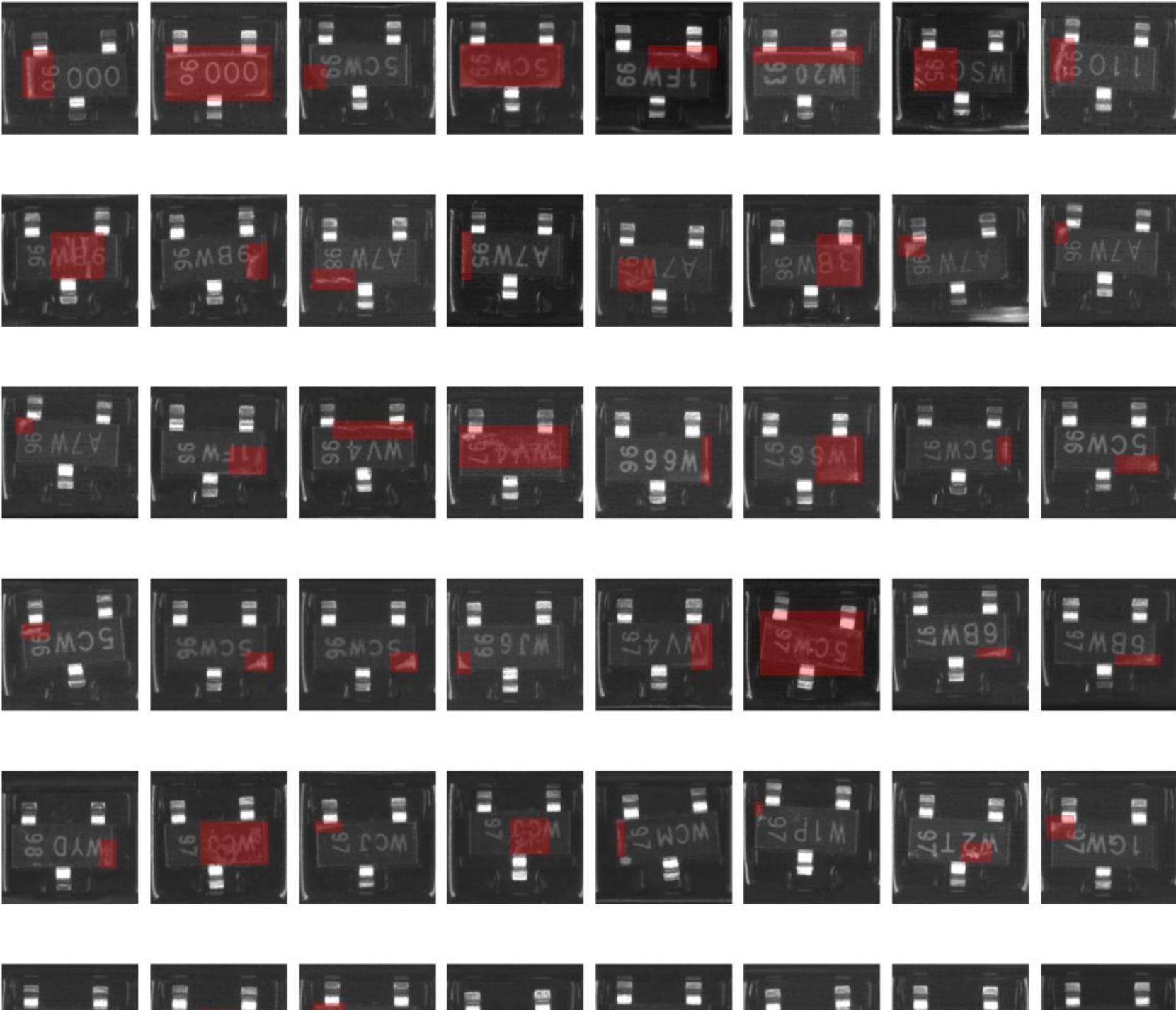
Defect Image...

Red rectangle: defect area

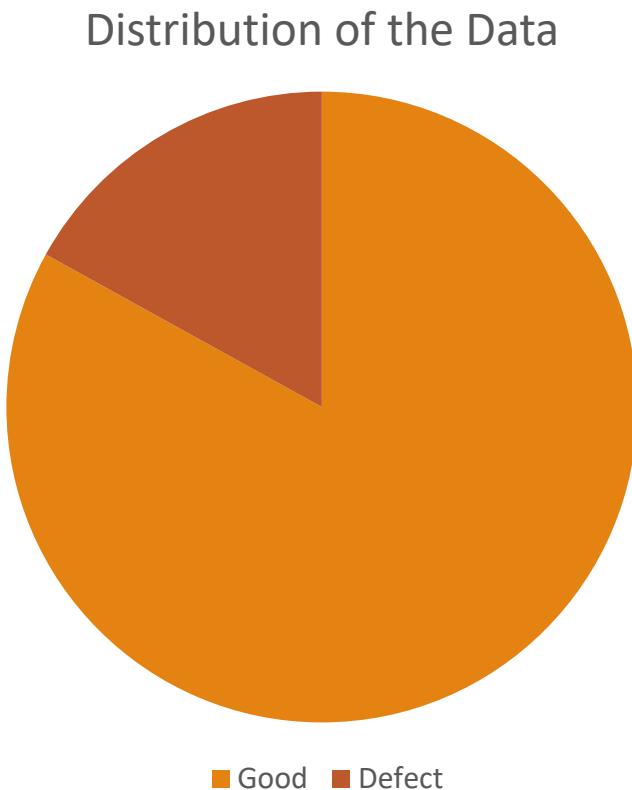
Observation

1. Some Scratch on the defect semi-conductor
2. There are some alphabet on the semi-conductor that might affect the classification

< defect_area.csv (335.75 KB)					
Detail	Compact	Column	# id	# x_1	# y_1
6696 unique values				0	241
SOT23DUMMY01_04-APG_ITIS_HS2_1_111_4	40		100	99	198
SOT23DUMMY01_09-APG_ITIS_HS2_1_12_3	28		98	242	204
WEA938001D1A_17-APG_ITIS_H49_1_48_2	10		131	52	179
WEA938001D1A_48-	25		86	229	175



Distribution of the data..



- Good 34459
- Defect 7039

Unbalance!



An orange, cloud-like graphic on the right side of the slide. Inside the cloud, the word "Unbalance!" is written in a white, sans-serif font, oriented diagonally upwards from left to right.

Testing Data have similar ratio...

Nexperia provided a dataset for Kaggle in-class contest that aims to classify images of semiconductor devices into two main classes, good and defect. For example, Fig. 1 shows a good example and a bad example. The Nexperia image dataset in the Kaggle contest contain 34457 train images (27420 good and 7039 bad) and 3830 test images with similar good-to-bad ratio. The key is to detect as many defect images as possible while not sacrificing too many passed ones. So on Kaggle contest, we adopt AUC, i.e. Area under the ROC Curve, as the evaluation metric. Note that AUC values are in the range of [0.5, 1], the higher, the better.

Oversampling / Undersampling → Lower the testing Score!

Oversampling / Under sampling?



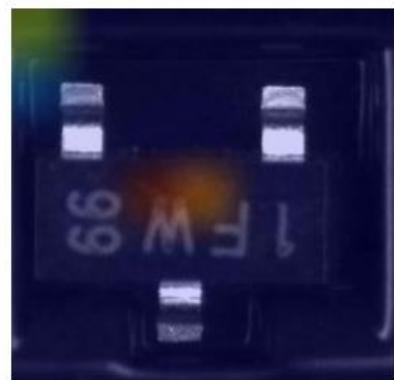
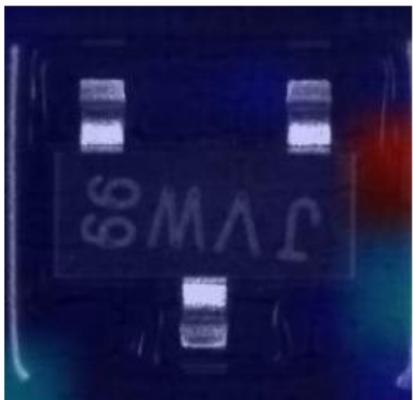
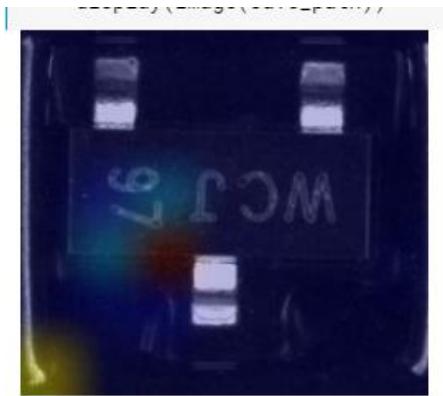
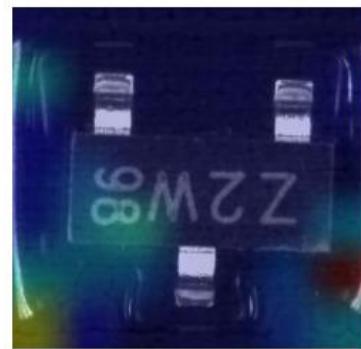
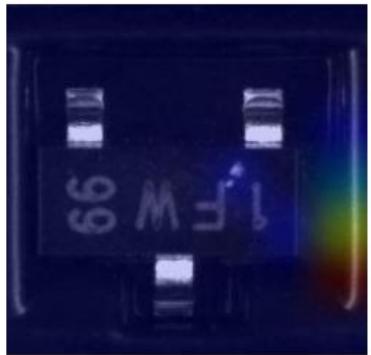
NO! The distribution of the test set have similar distribution as the training one.

Method 1

1. Remove the boundary ~20 pixels
2. ~~Normalize the color~~
3. For the brightness of pixel lower than 0.2, set it to 0 directly.
4. ~~Mean Filter~~



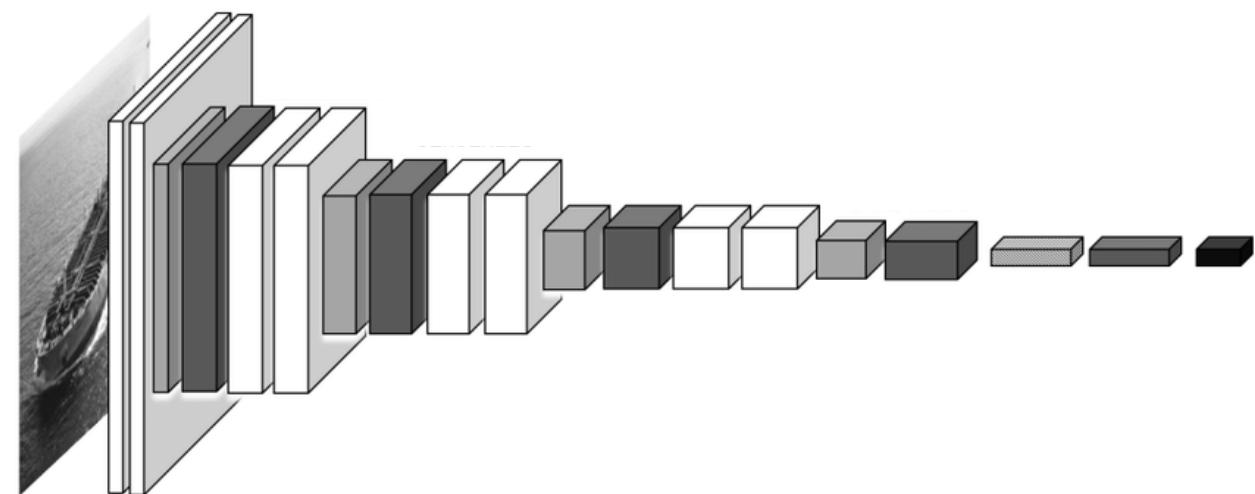
Why remove the boundary?



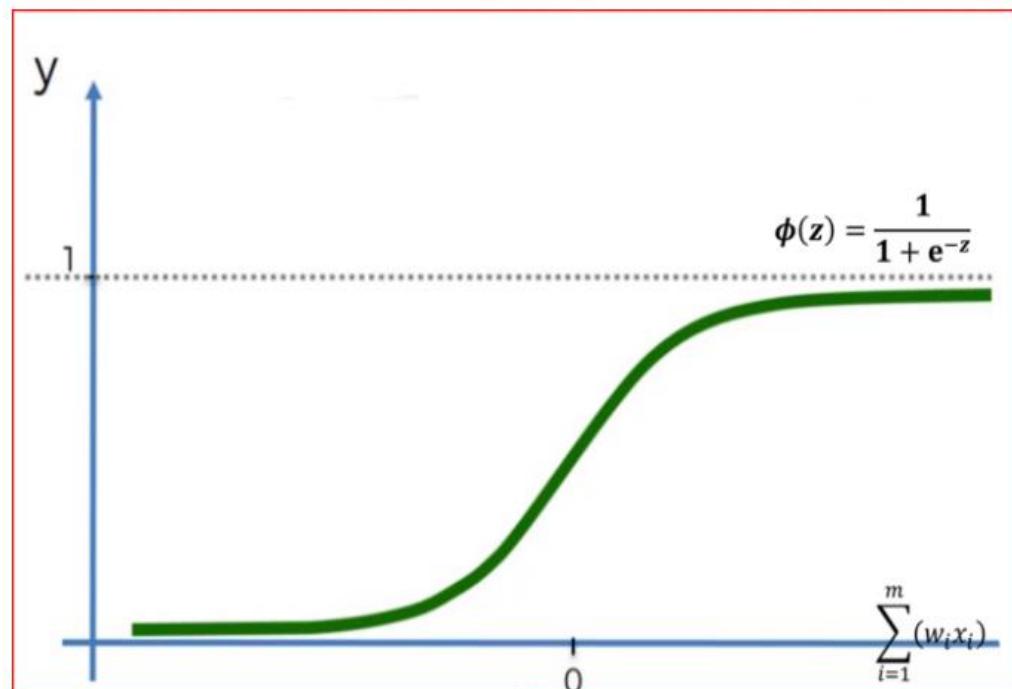
These are Good
Sample indeed!!

Layer (type)	Output Shape	Pa
conv2d_3 (Conv2D)	(None, 192, 192, 16)	41
batch_normalization_4 (Batch Normalization)	(None, 192, 192, 16)	64
max_pooling2d_3 (MaxPooling2)	(None, 96, 96, 16)	0
conv2d_4 (Conv2D)	(None, 96, 96, 32)	12
batch_normalization_5 (Batch Normalization)	(None, 96, 96, 32)	12
max_pooling2d_4 (MaxPooling2)	(None, 48, 48, 32)	0
conv2d_5 (Conv2D)	(None, 48, 48, 64)	51
batch_normalization_6 (Batch Normalization)	(None, 48, 48, 64)	25
max_pooling2d_5 (MaxPooling2)	(None, 24, 24, 64)	0
dropout_1 (Dropout)	(None, 24, 24, 64)	0
flatten_1 (Flatten)	(None, 36864)	0
dense_2 (Dense)	(None, 128)	47
batch_normalization_7 (Batch Normalization)	(None, 128)	51
dense_3 (Dense)	(None, 1)	12

Let's build a **simple CNN model**



Activation Function of Last Layer



Sigmoid Activation Function

It **predicts the probability of an output** and hence is **used in output layers of a neural network and logistics regression**

As the probability ranges from 0 to 1, so sigmoid function value exists between 0 and 1

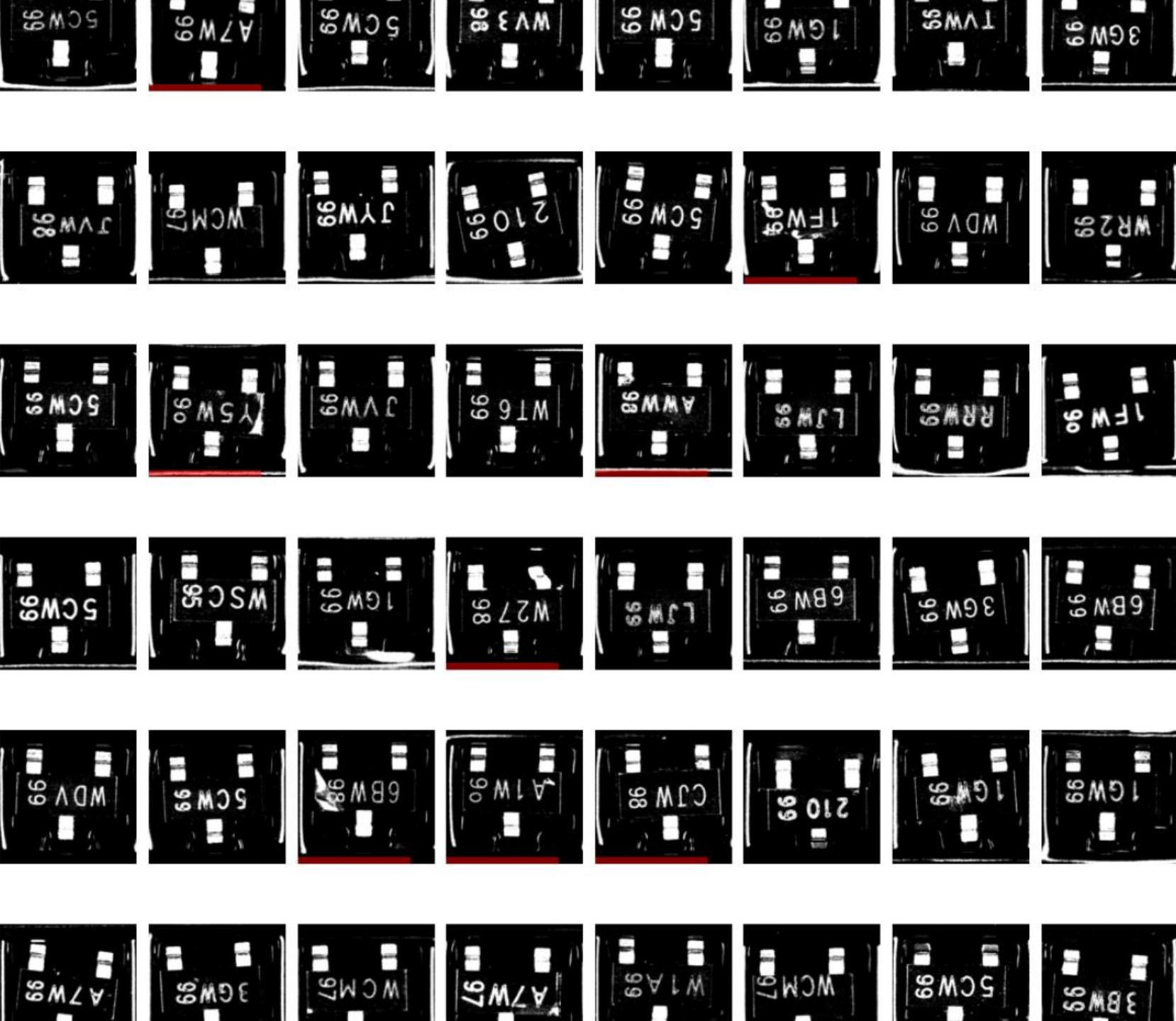
<https://arshren.medium.com/neural-networks-activation-functions-e371202b56ff#:~:text=Sigmoid%20activation%20function%20is%20used,should%20be%20equal%20to%201.>

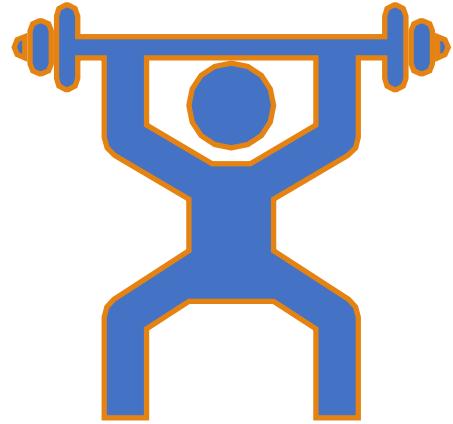
Softmax: Output Class = 2 | Sigmoid: Output Class = 1

Processing 2

Black and white filter

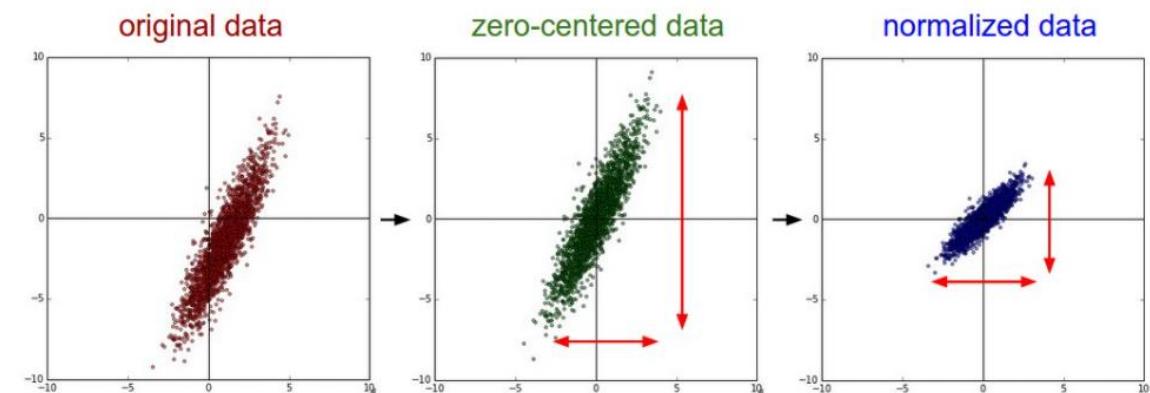
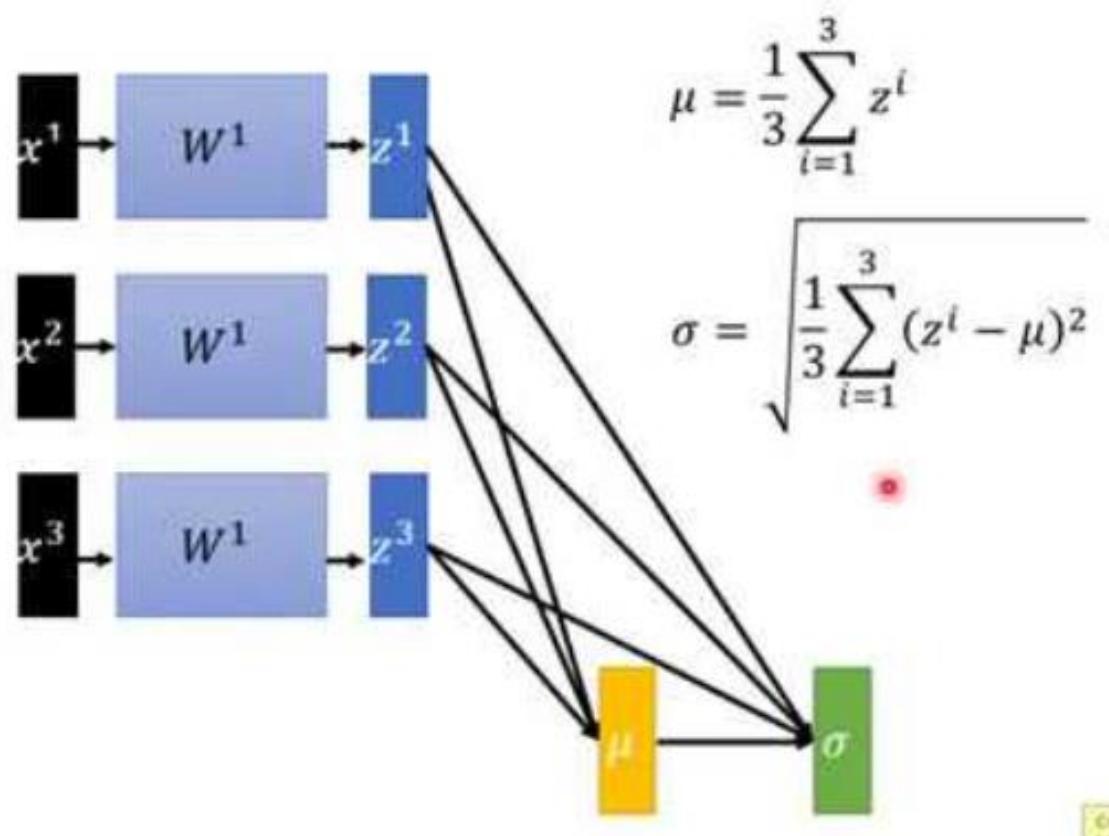
AUC: ~ 50-75



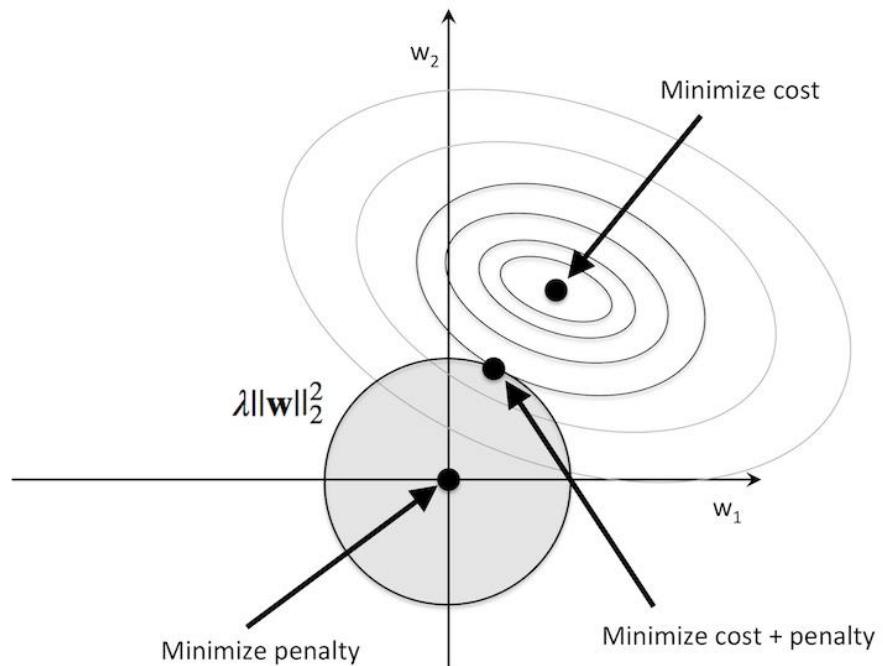


Some Training Technique...

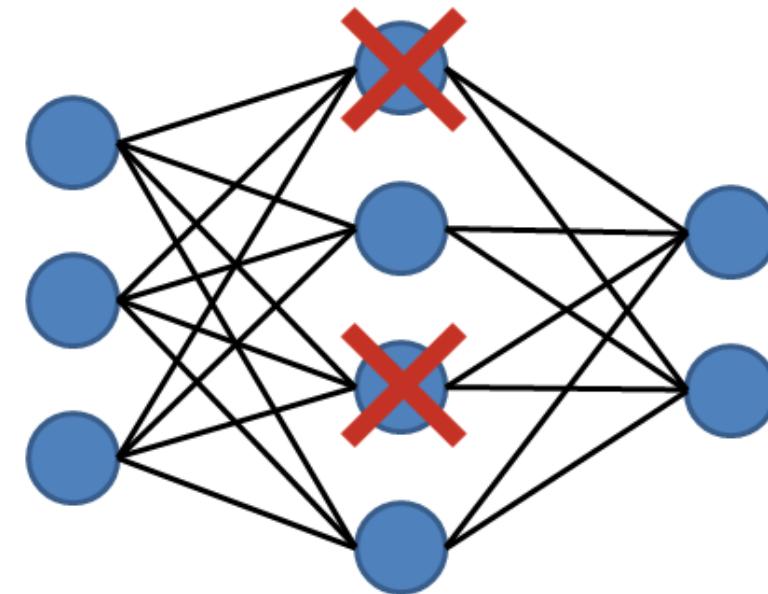
Batch Normalization



To prevent overfitting...

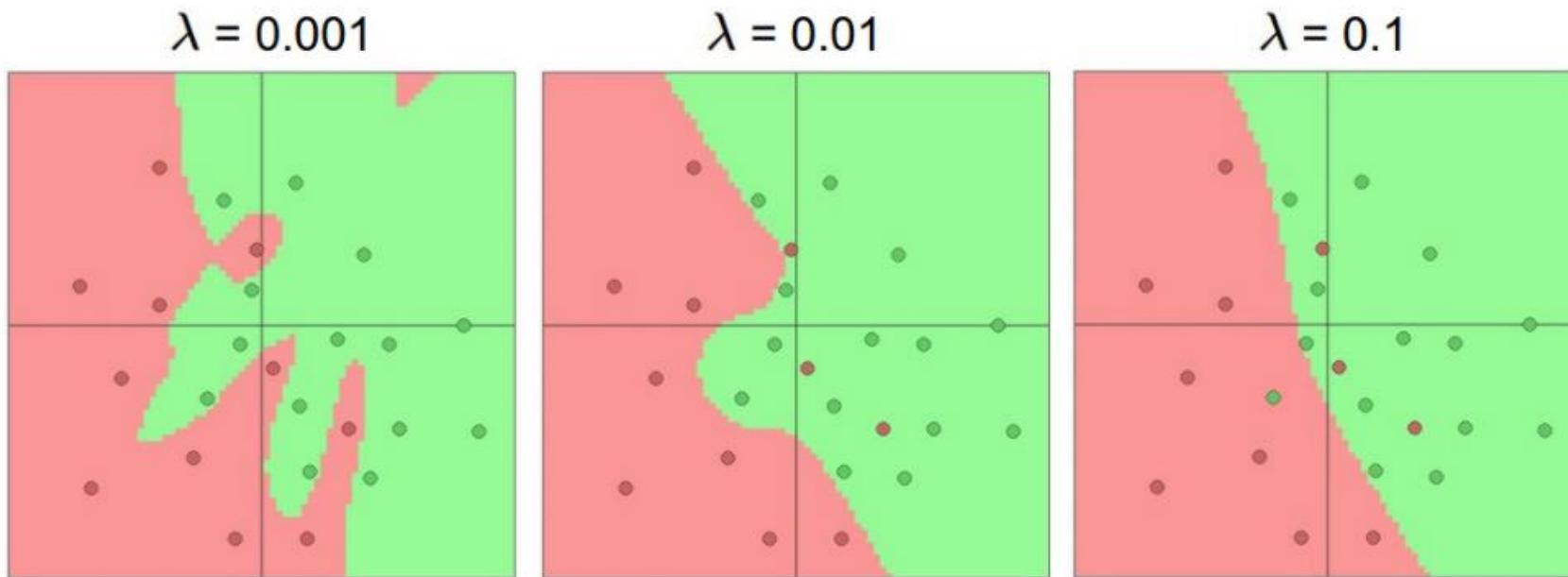


L2 regularization



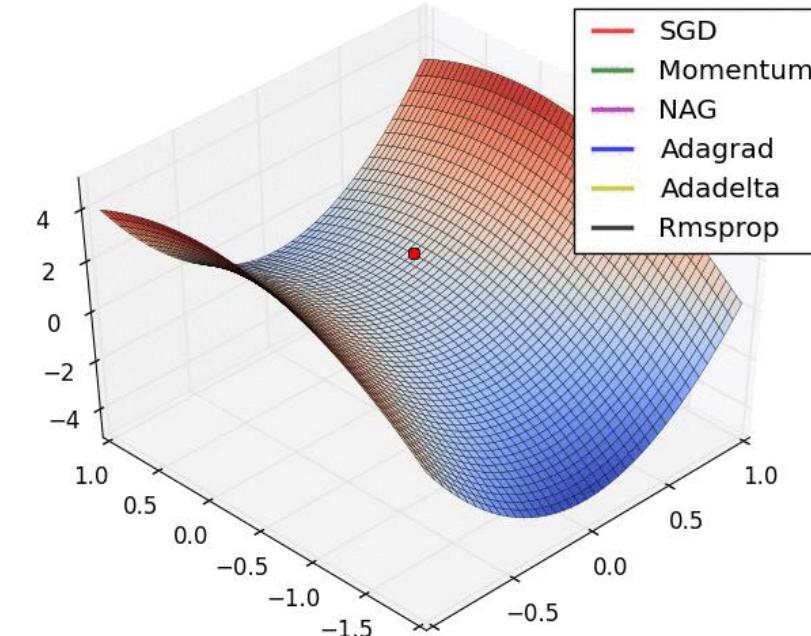
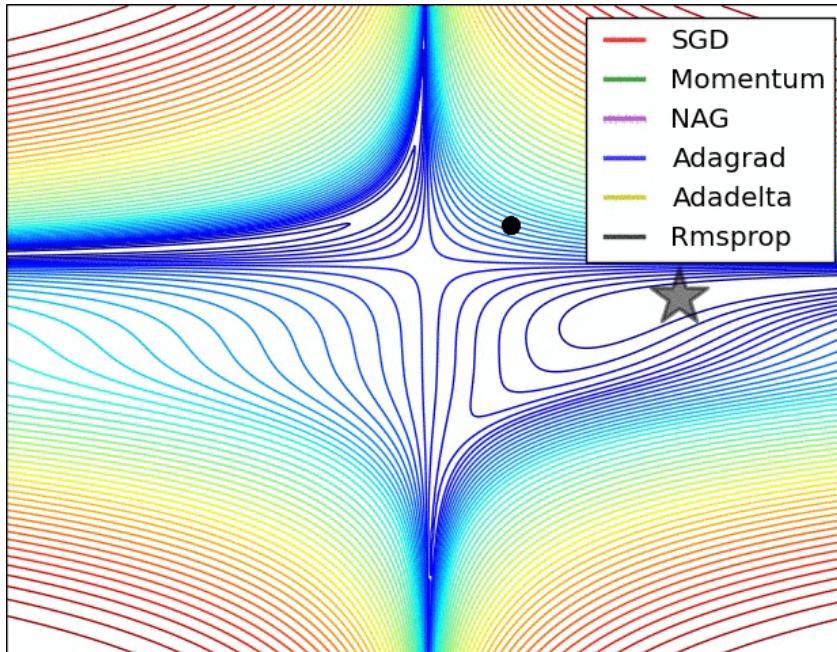
Dropout

Regularization



The effects of regularization strength: Each neural network above has 20 hidden neurons, but changing the regularization strength makes its final decision regions smoother with a higher regularization. You can play with these examples in this [ConvNetsJS demo](#).

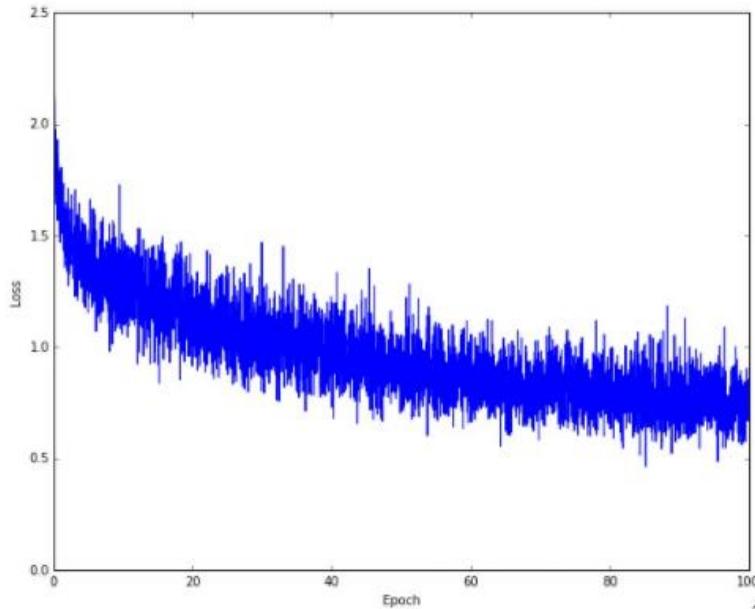
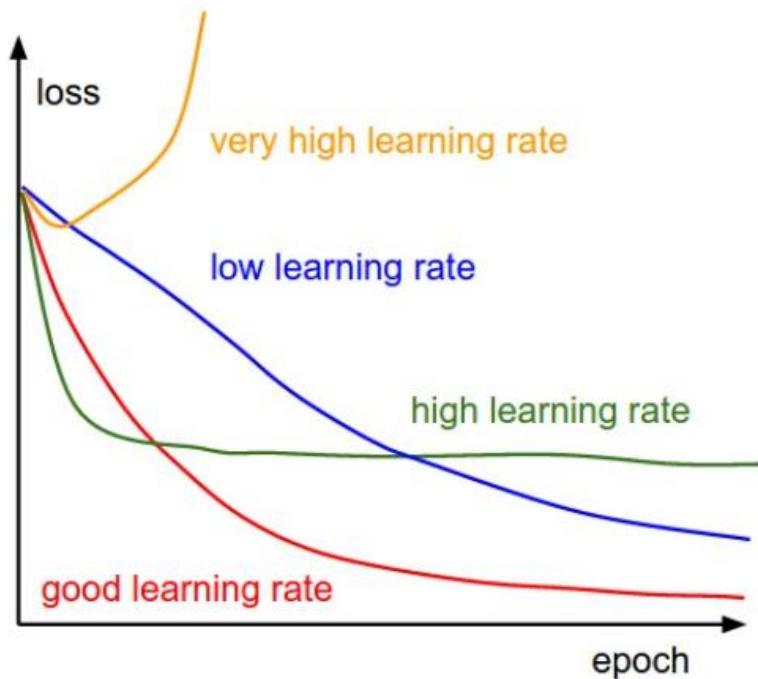
Optimizer



Benefit

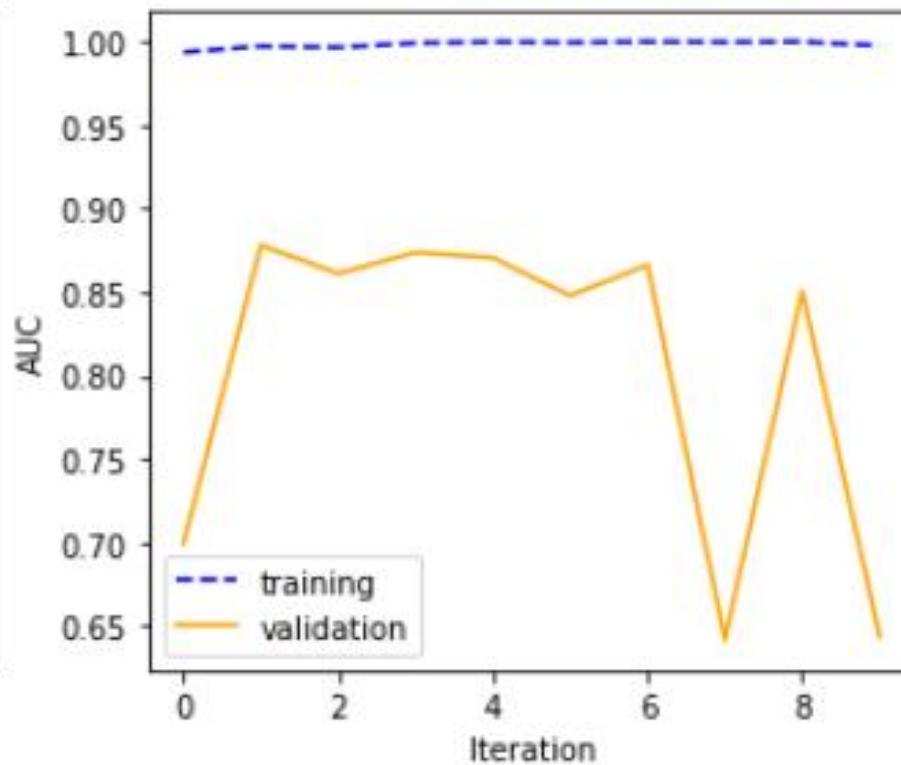
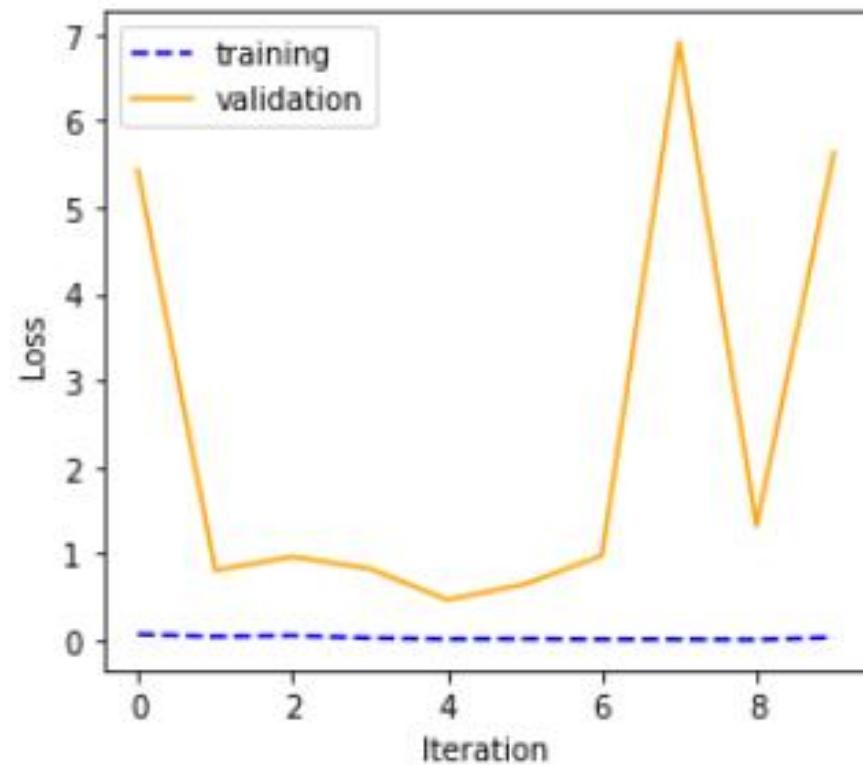
- ✓ The performance improves
- ✓ the curves becomes smoother.

Good Training Rate?

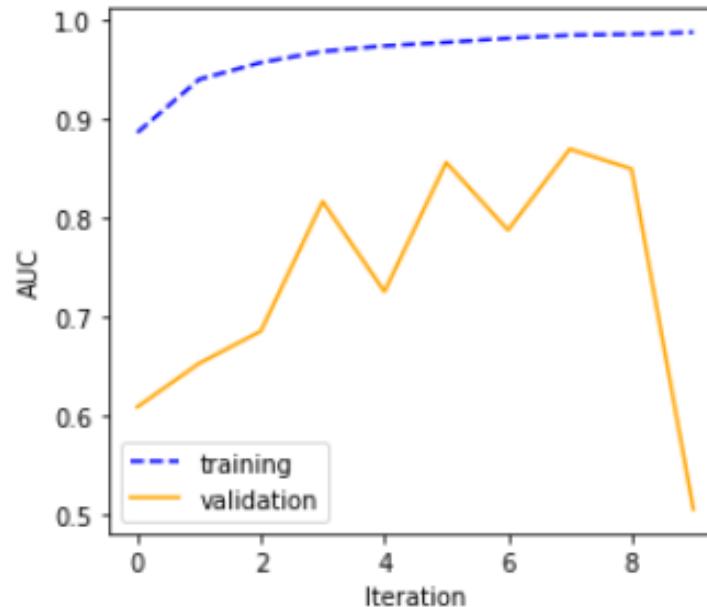
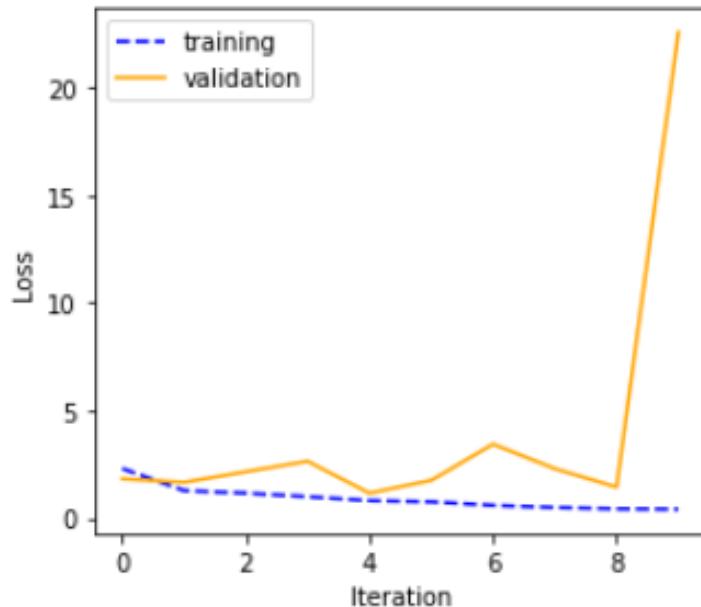


Training rate will auto decay...

Some Attempt..

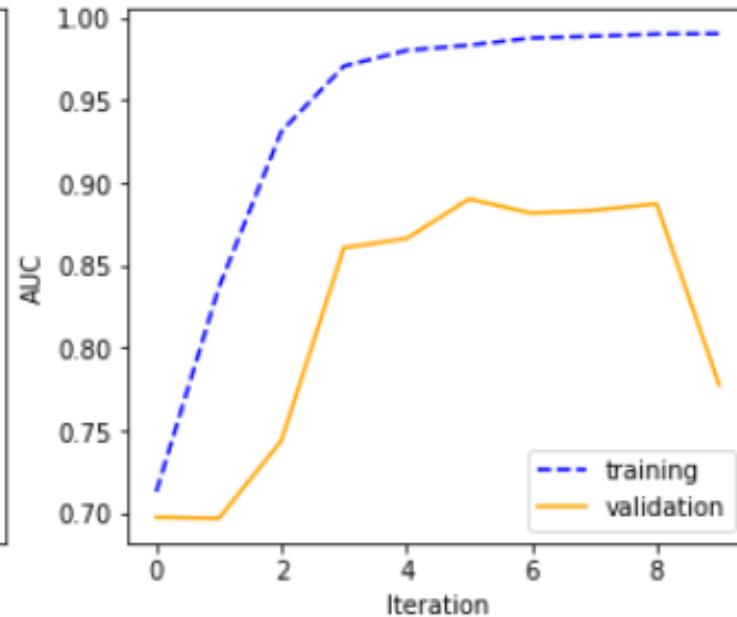
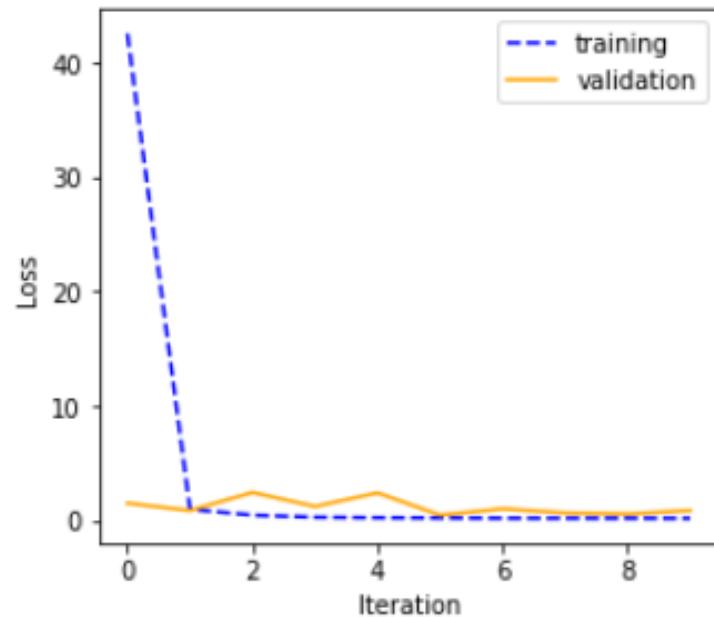


Some Attempt..



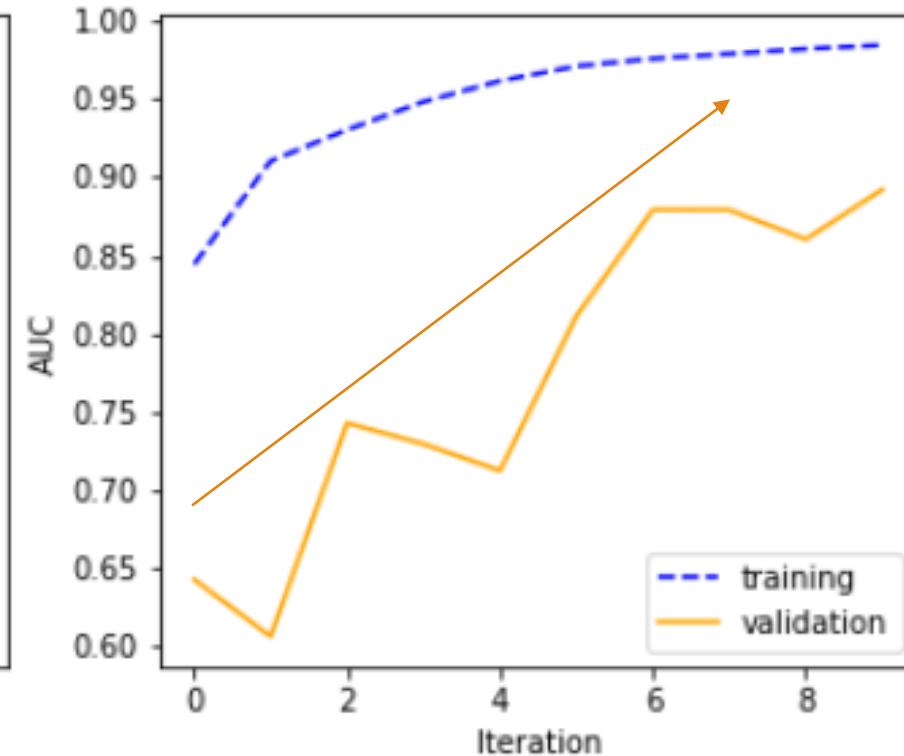
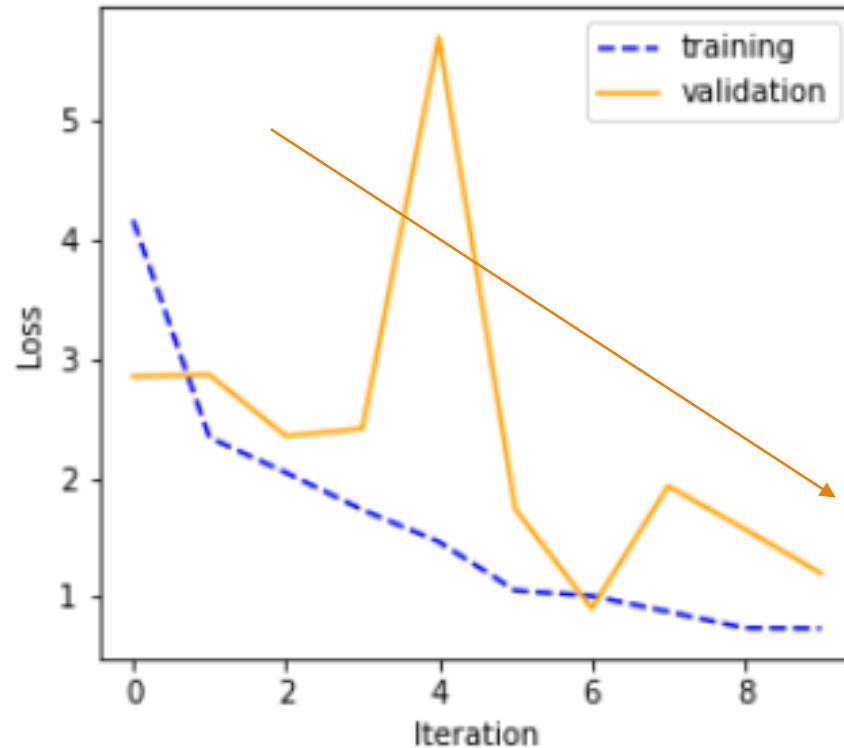
Add Dropout...

Some Attempt..



Stronger...

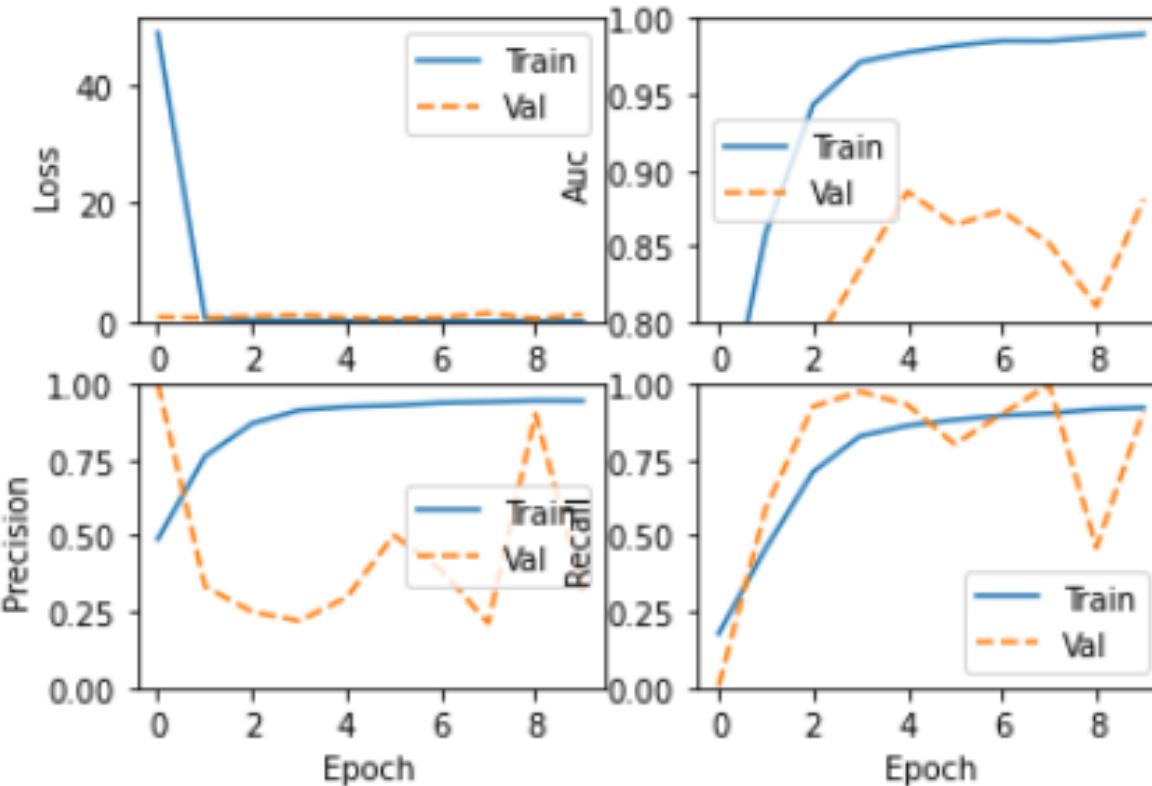
Is it Better?



Stronger...

However, we should also focus on the AUC, precision and recall

Especially Precision



Precision and Recall

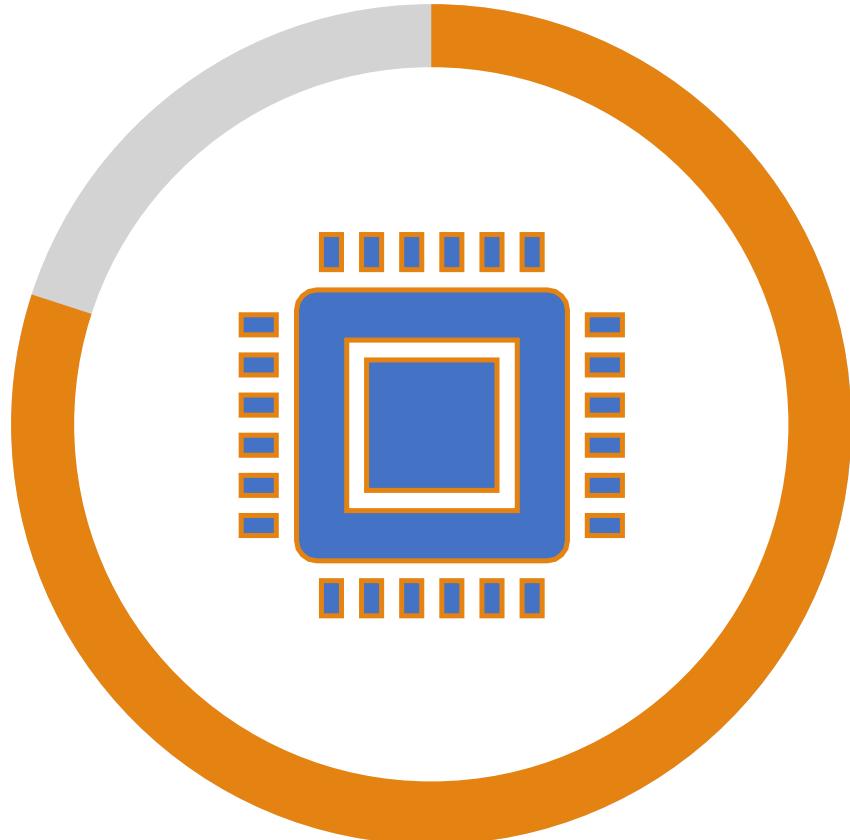
		Real Label	
		Positive	Negative
Predicted Label	Positive	True Positive (TP)	False Positive (FP)
	Negative	False Negative (FN)	True Negative (TN)

$\rightarrow \text{Precision} = \frac{\sum \text{TP}}{\sum \text{TP} + \text{FP}}$

\downarrow

$\text{Recall} = \frac{\sum \text{TP}}{\sum \text{TP} + \text{FN}}$

$\text{Accuracy} = \frac{\sum \text{TP} + \text{TN}}{\sum \text{TP} + \text{FP} + \text{FN} + \text{TN}}$



Just use 80% of the
training Data for the
below Model...

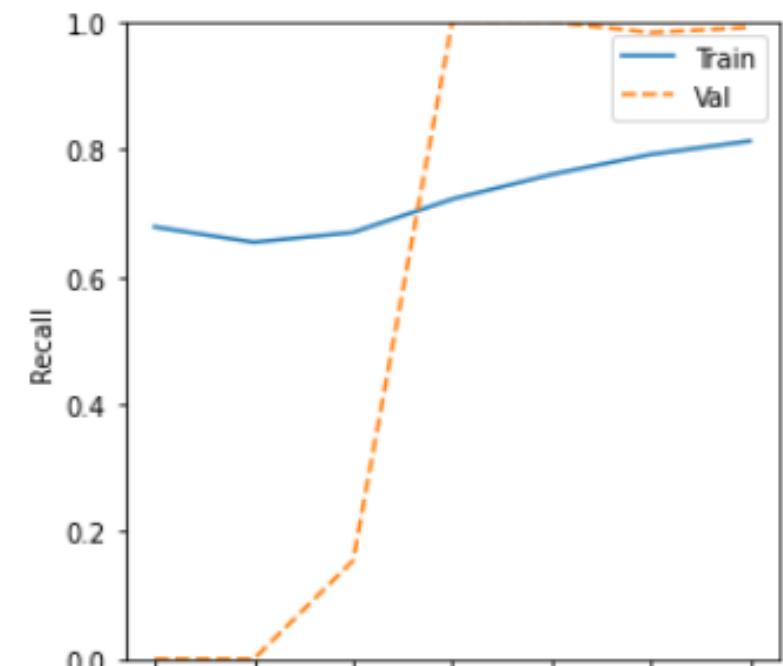
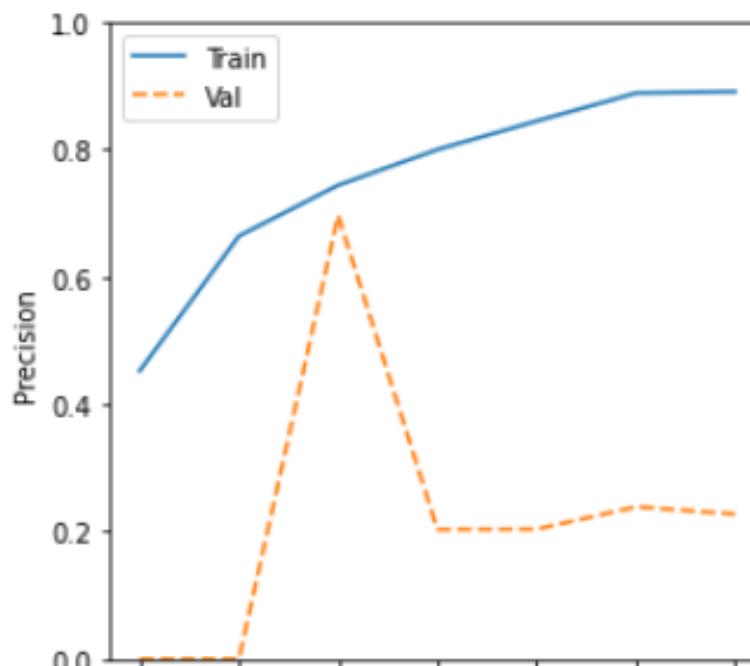
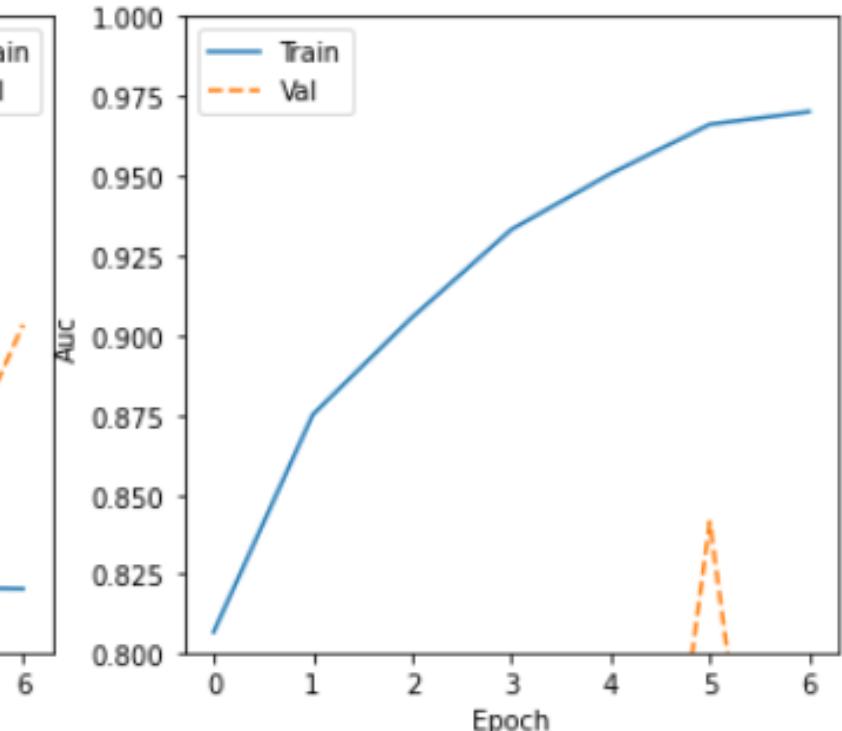
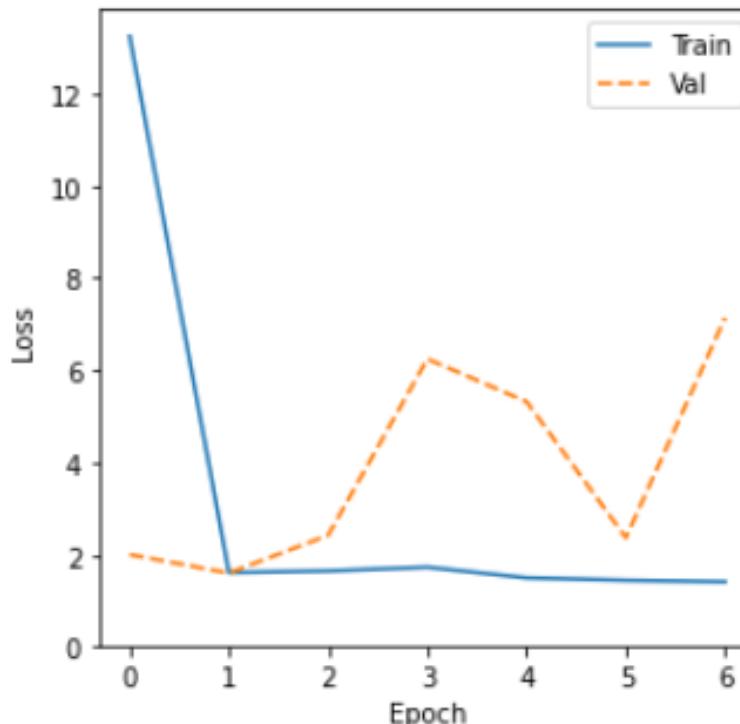
The AUC will be higher when using 100% of the training Data for prediction

Bad Model

Accuracy : 79.5%,

AUC : achieve 69.86%

```
loss : 1.6043896675109863
tp : 0.0
fp : 0.0
tn : 5484.0
fn : 1407.0
accuracy : 0.7958206534385681
precision : 0.0
recall : 0.0
auc : 0.6986060738563538
```

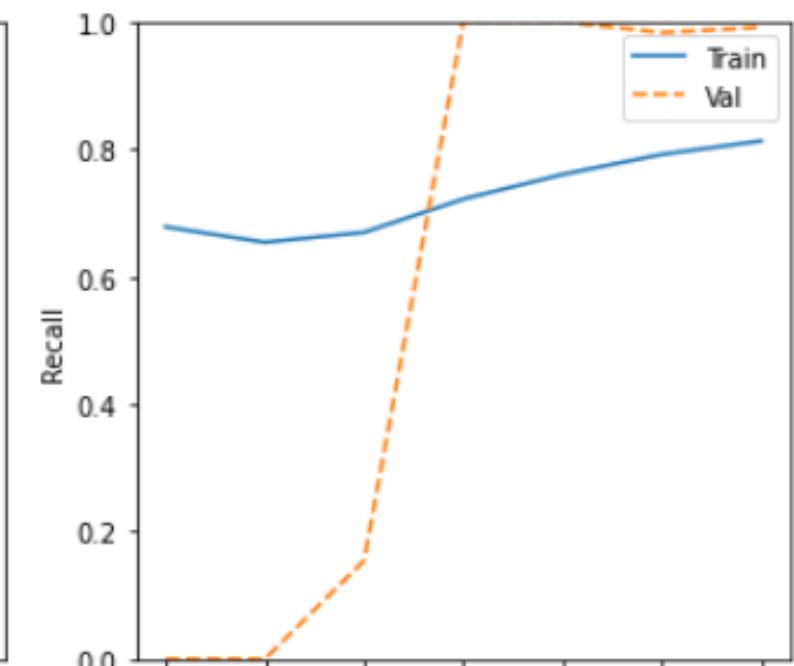
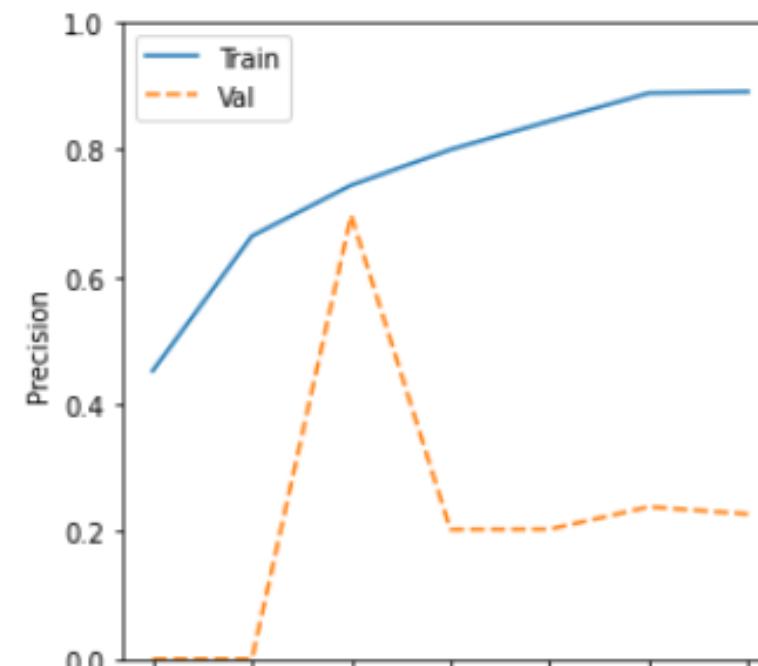
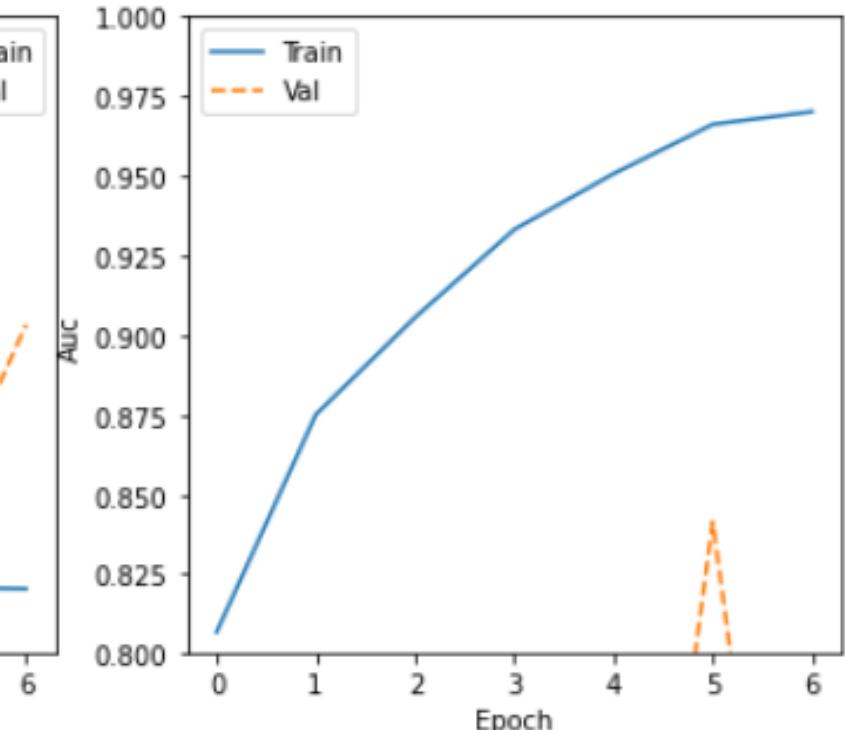
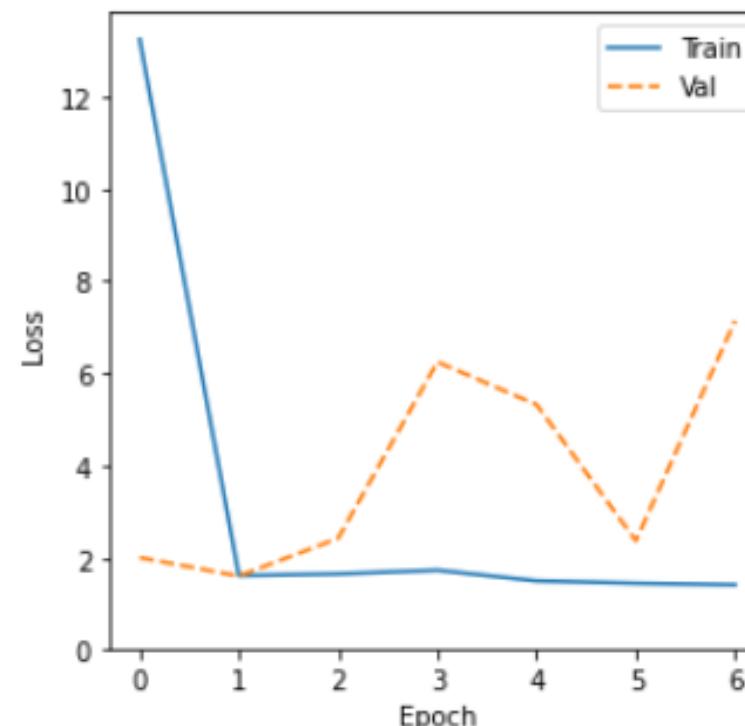
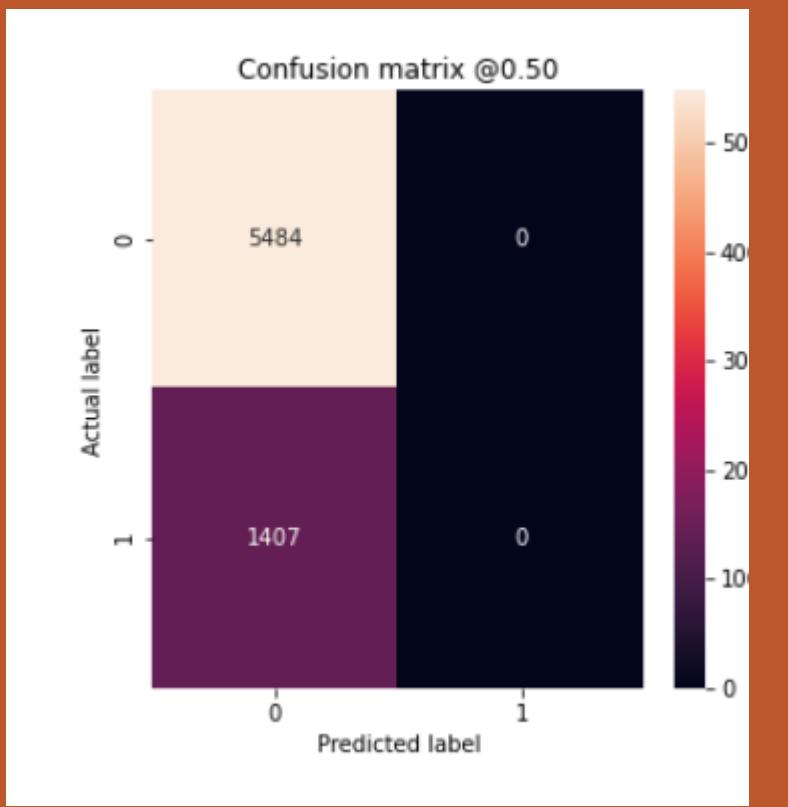


Bad Model

This model always predict 0.

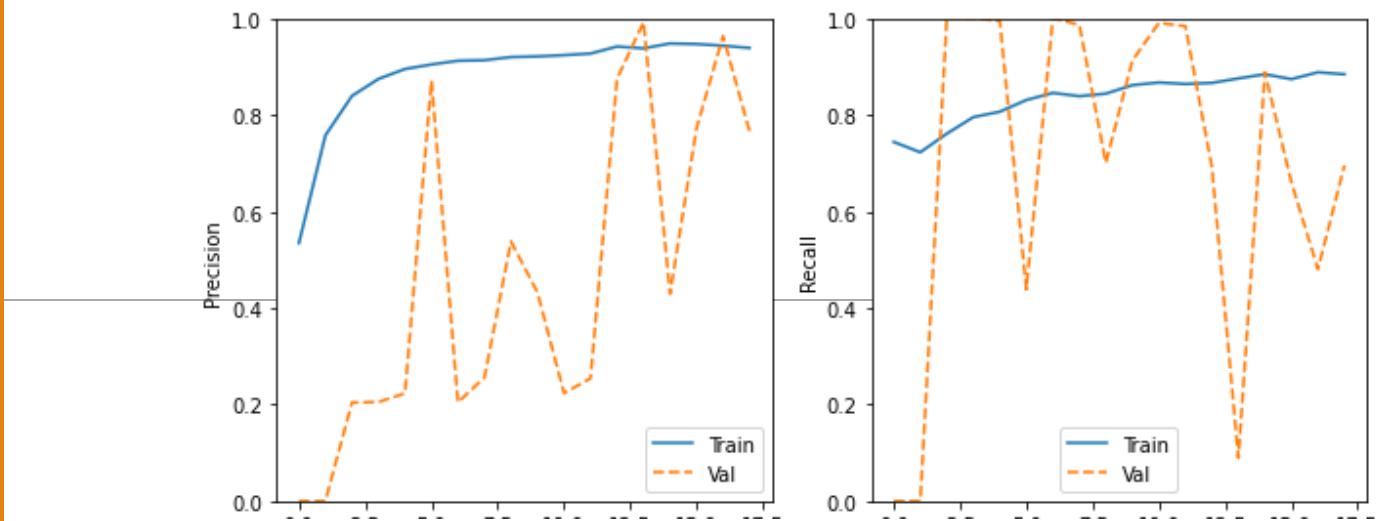
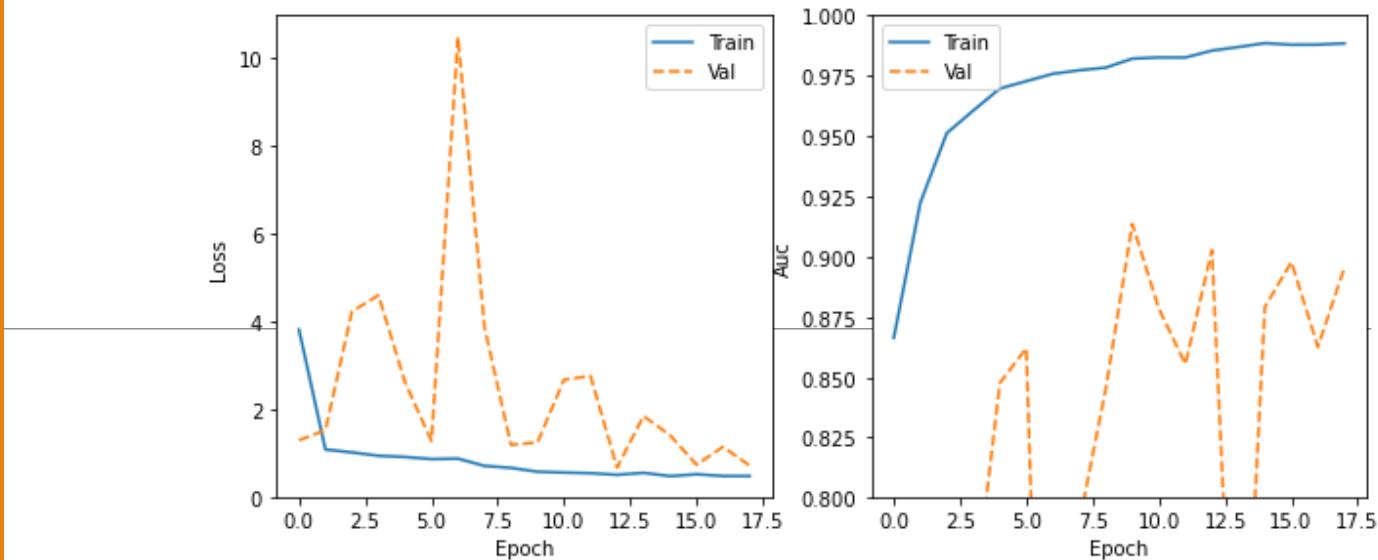
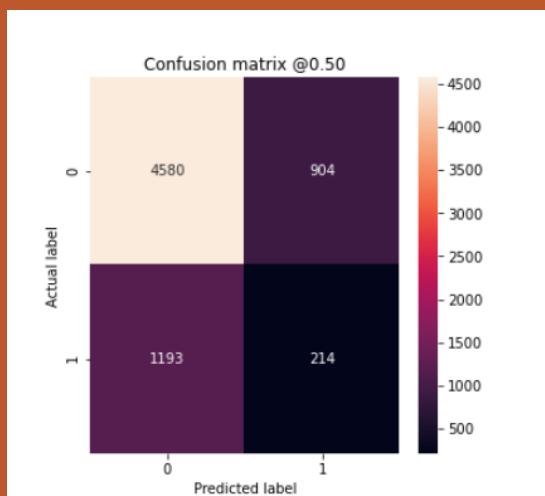
The Recall can achieve 100% but ..

Precision : $1407 / (5484 + 1407) = 20.4\%$



Much Better Model

```
loss : 0.6841353178024292
tp : 978.0
fp : 140.0
tn : 5344.0
fn : 429.0
accuracy : 0.9174285531044006
precision : 0.8747763633728027
recall : 0.695095956325531
auc : 0.9035826921463013
```



submission.csv
10 days ago by kinkinww
add submission details

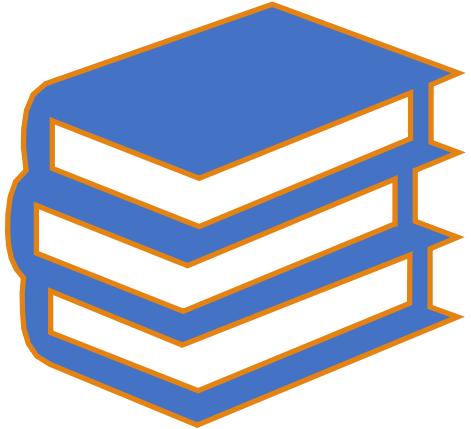
0.97593



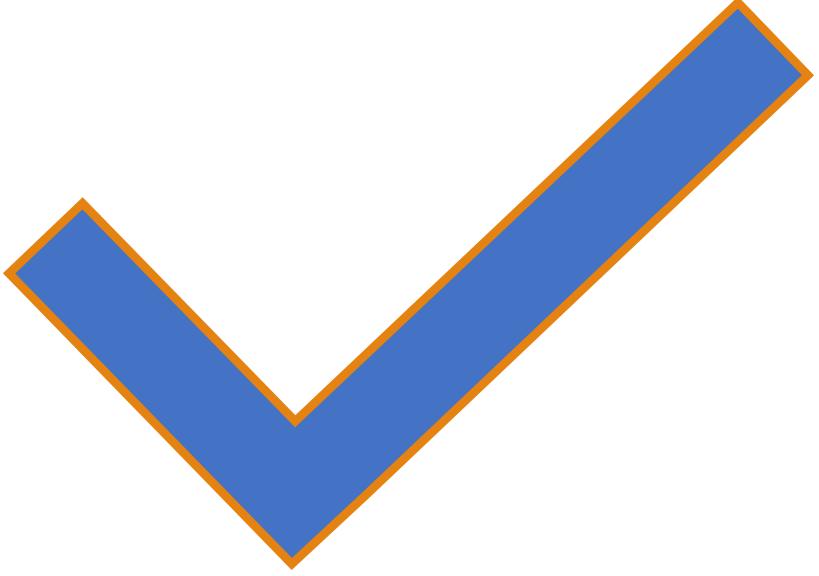
Drawback of CNN

Training Time is too long.

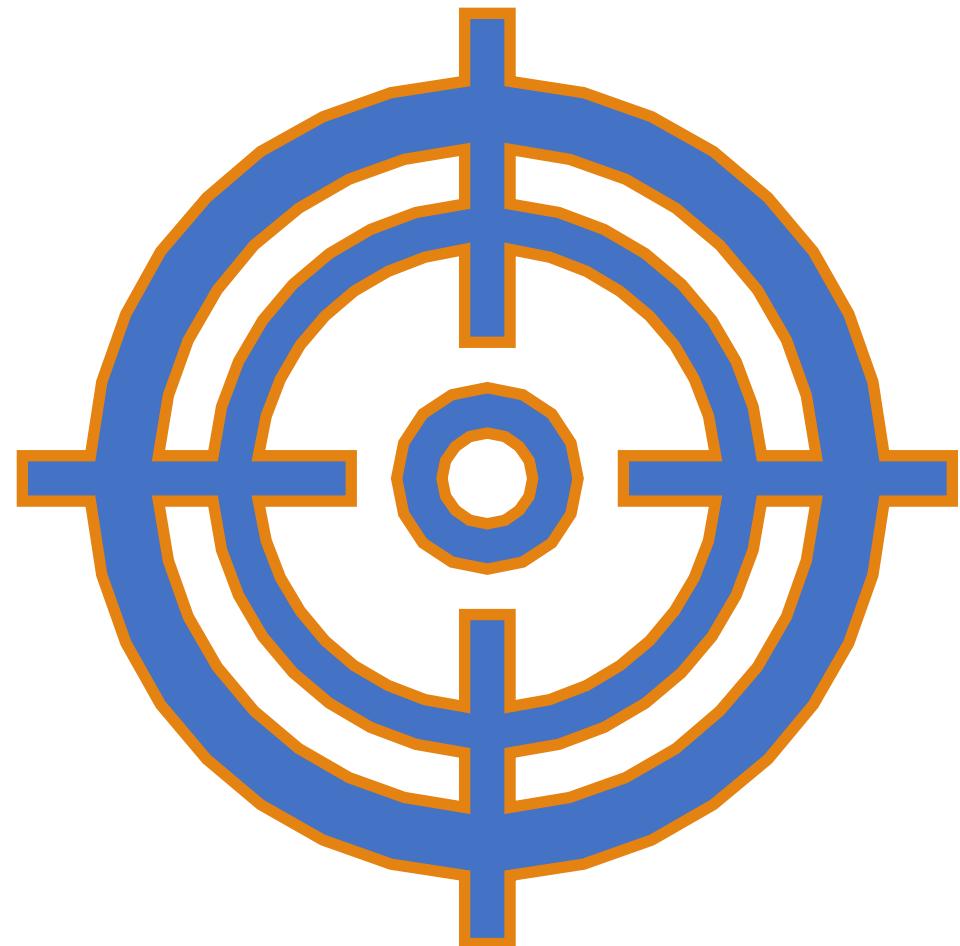
- 3-5 minutes per Epoch



Test AUC always higher
than Training AUC~



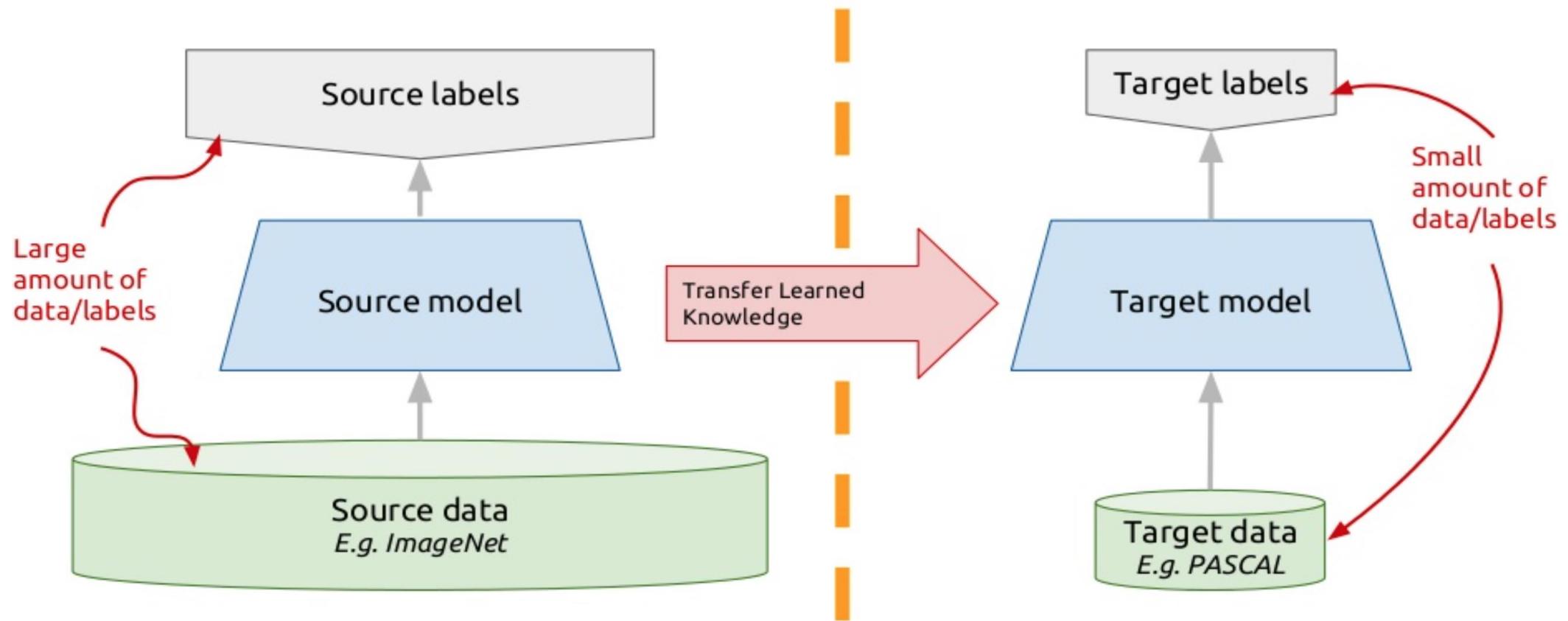
Save the best
Model can always
achieve higher
Testing AUC



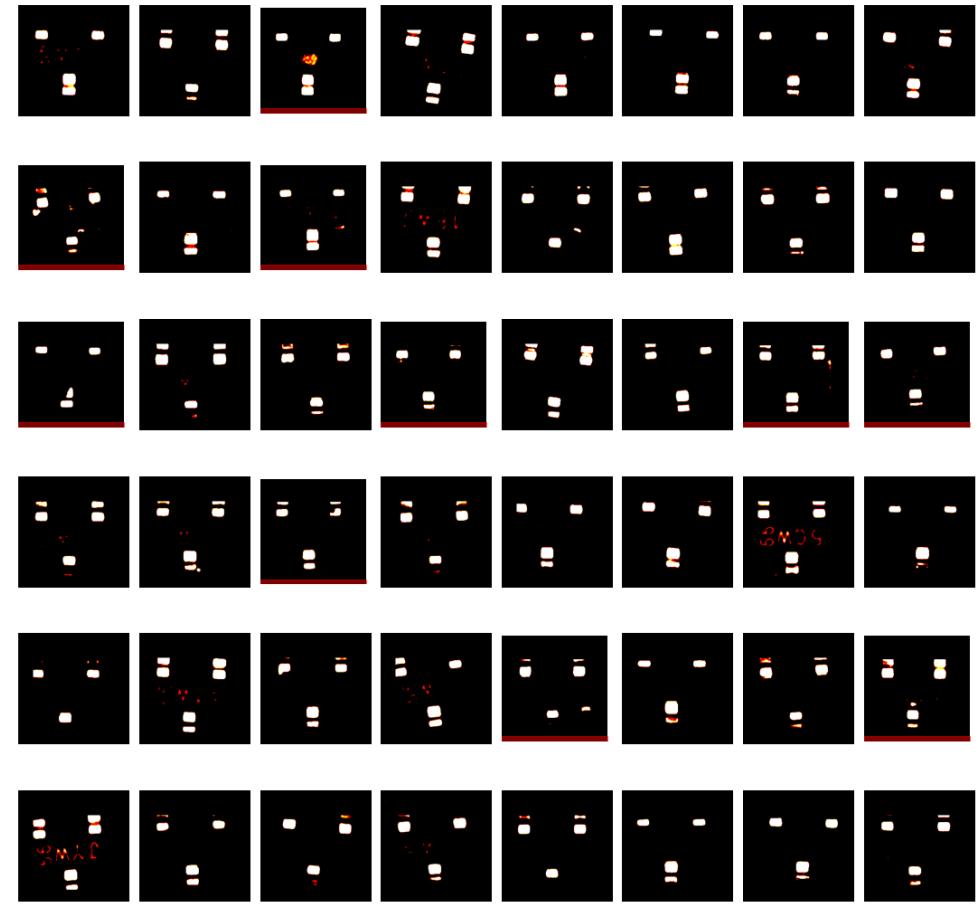
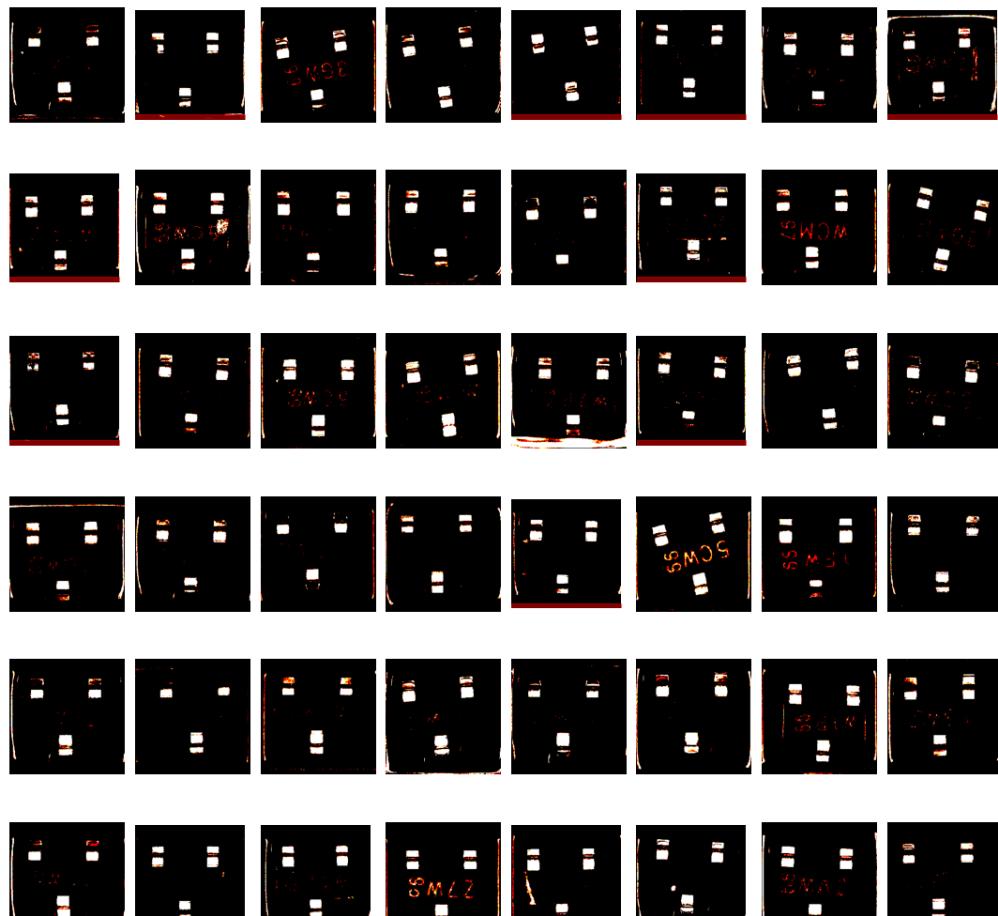
Some Observation

- Neither Training AUC nor Training Accuracy can achieve 100% after applying stronger regularization, dropout =[
- Noise label??

Transfer Learning with RESNET50



Preprocessing function in resnet



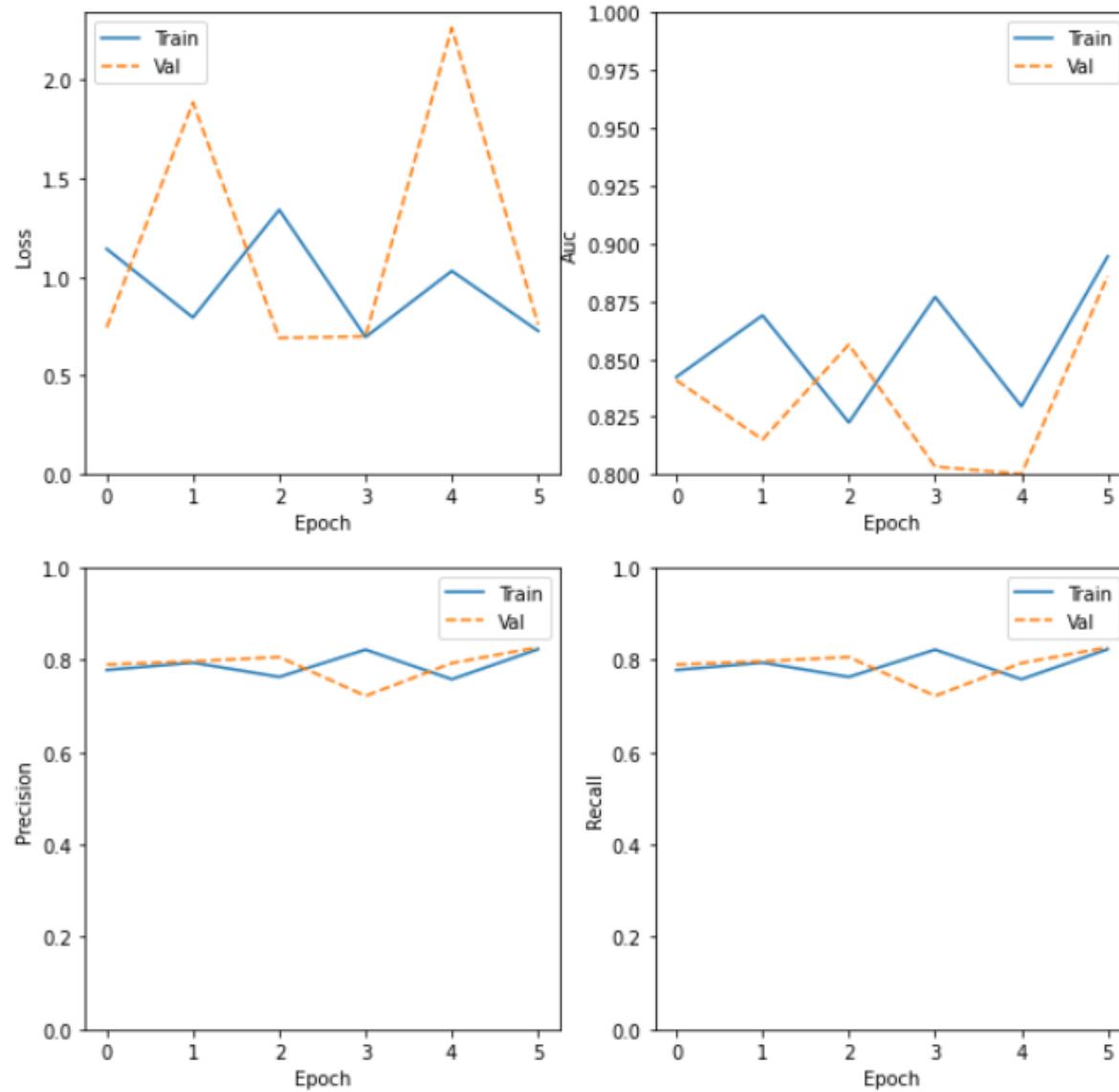
Transfer Learning RESNET50

- ✓ High Performance already in 1st Epoch??
- ✓ The Parameter is wrong in this model... :(

```
Model: "sequential"
-----
Layer (type)          Output Shape       Param #
-----
resnet50 (Functional) (None, 2048)      23587712
dense (Dense)         (None, 2)           4098
-----
Total params: 23,591,810
Trainable params: 4,098
Non-trainable params: 23,587,712
```



plot_metrics(fit_history)

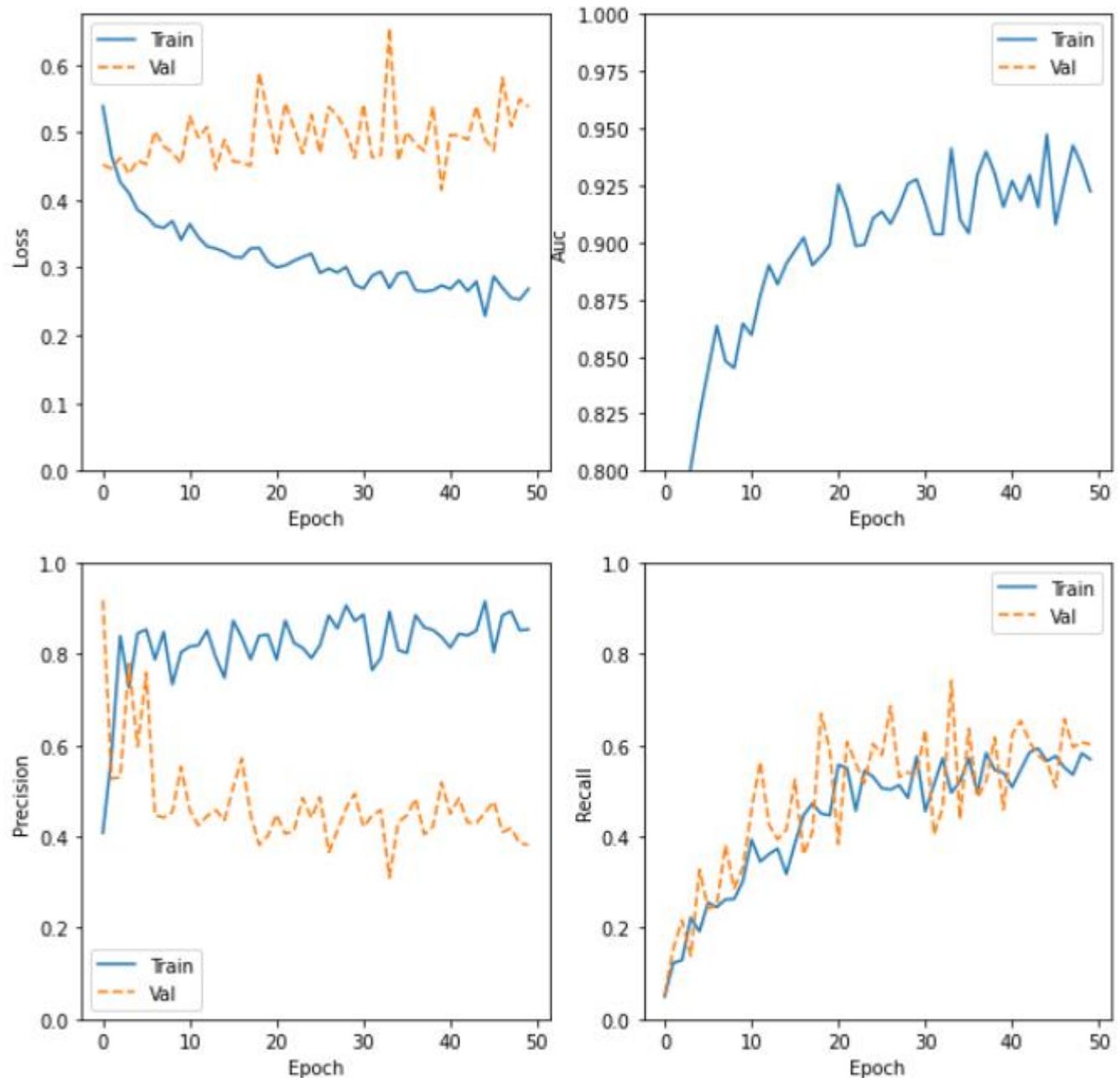


Transfer Learning RESNET50

Only Train the top layer

Total params: 23,591,810
Trainable params: 4,098
Non-trainable params: 23,587,712

Score
0.88462



Transfer Learning RESNET50

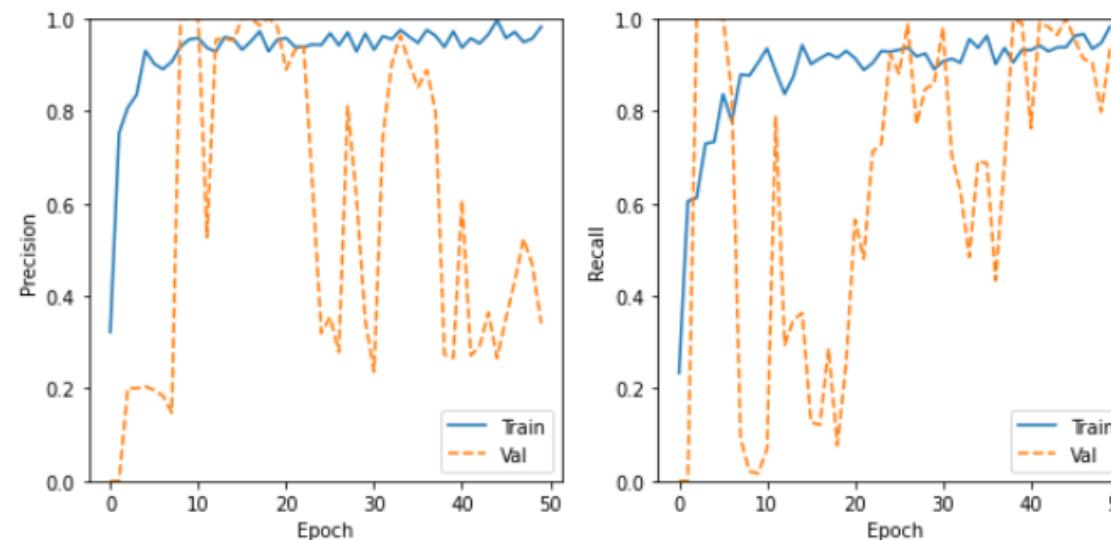
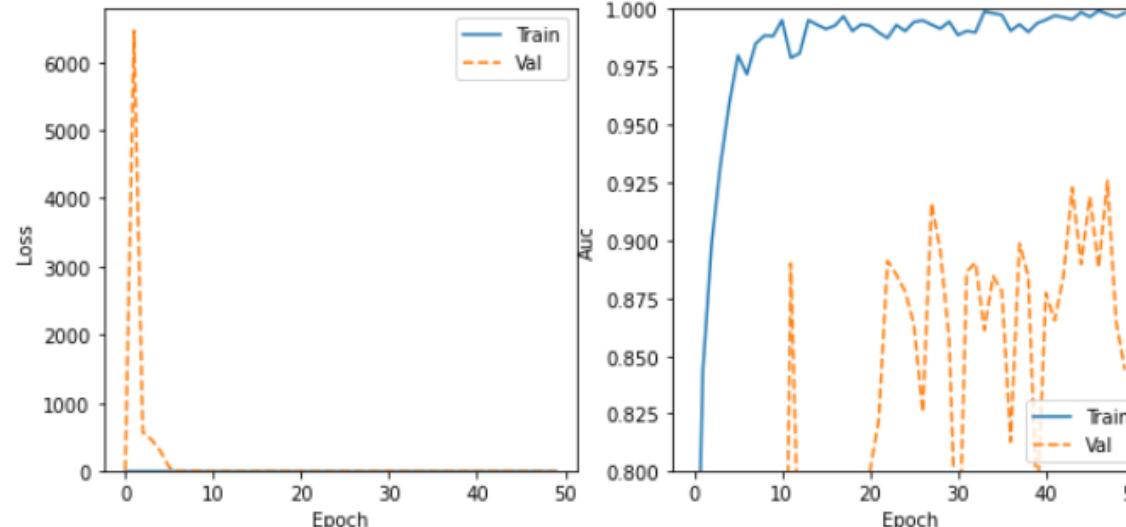
Fine Tune the model

Training AUC: 0.9949

Val AUC : 0.94024

Testing AUC: 0.98376

Score
0.98376



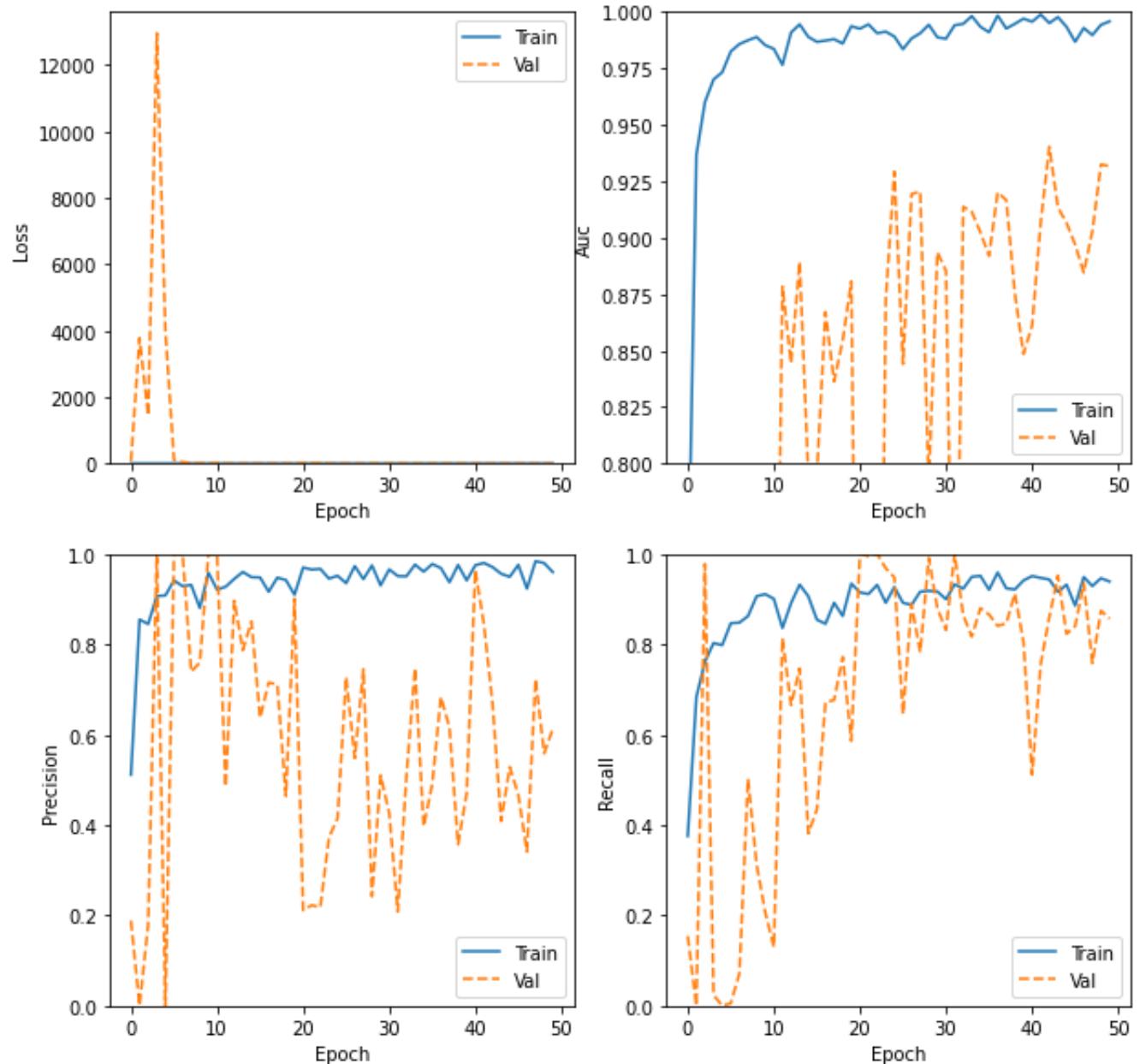
```
10/10 [=====] - ETA: 0s - loss: 0.0573 - tp: 200.0000 - fp: 6.0000 - tn: 782.0000 - fn: 12.0000 - accuracy: 0.9820 - precision: 0.9709 - recall: 0.9434 - auc: 0.9949
Epoch 00043: val_auc improved from 0.92916 to 0.94024, saving model to ../working/best.hdf5
```

Transfer Learning

Fine Tune the model

With Dropout

Score
0.98376

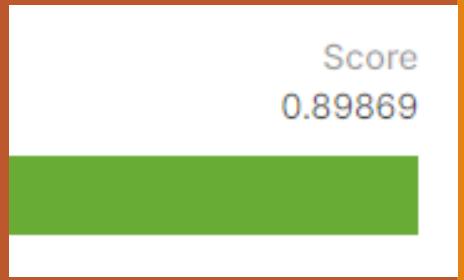


Transfer Learning VGG

Only Train the top layer

Trainable Parameter: ~513 only

100 Epoch



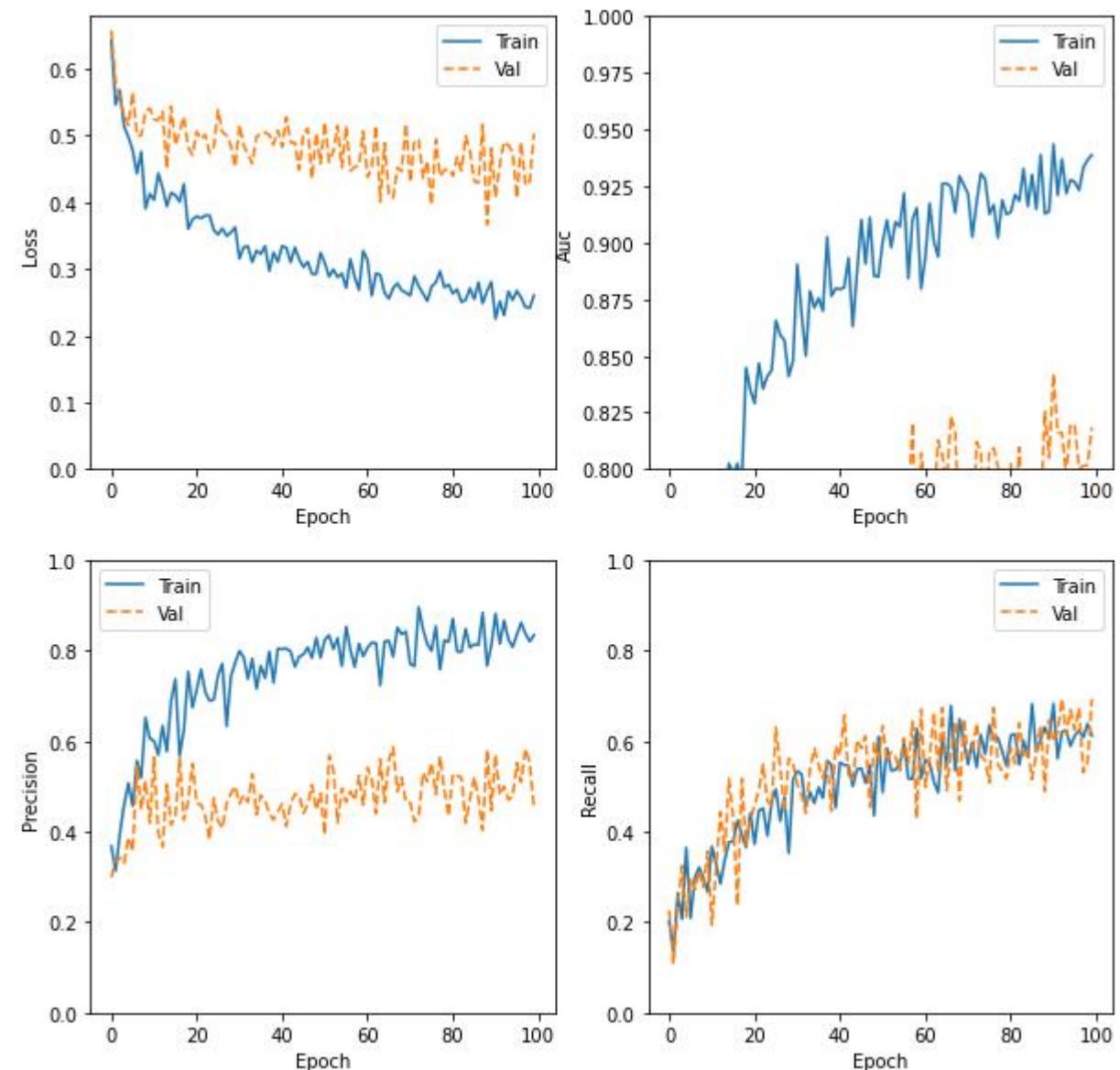
Model: "sequential_3"

Layer (type)	Output Shape	Param #
vgg16 (Functional)	(None, 512)	14714688
dense_3 (Dense)	(None, 1)	513

Total params: 14,715,201

Trainable params: 513

Non-trainable params: 14,714,688



Transfer Learning VGG

Fine Tuning

Trainable Parameter: ~14714688

100 Epoch

Always predict Negative

Gradient Gone...?

Nothing to see...

```
Model: "sequential_4"
-----

| Layer (type)       | Output Shape | Param #  |
|--------------------|--------------|----------|
| vgg16 (Functional) | (None, 512)  | 14714688 |
| dense_4 (Dense)    | (None, 1)    | 513      |


-----  
Total params: 14,715,201  
Trainable params: 14,715,201  
Non-trainable params: 0
```

Some evaluation...

After 30 something epoch will have the best model.

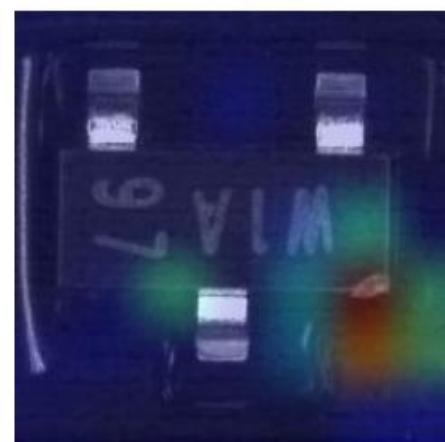
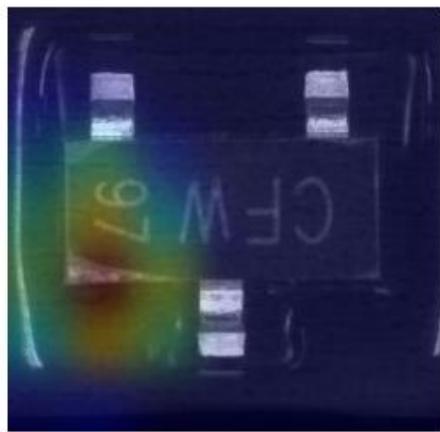
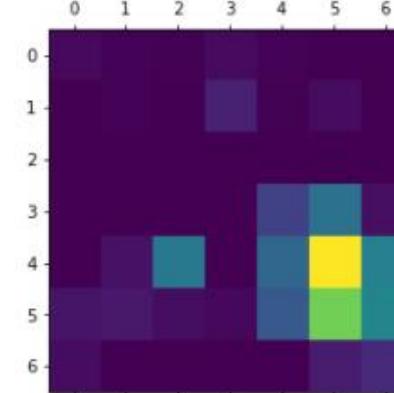
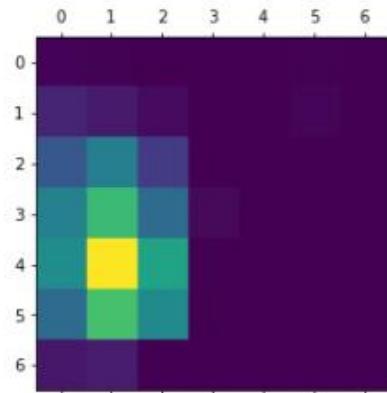
Just train 1-2 epoch can also get a high testing AUC ! (~0.97)

Fine Tuning can achieve higher AUC then just training the last layer



AUC mean what?

Grad-CAM class activation visualization

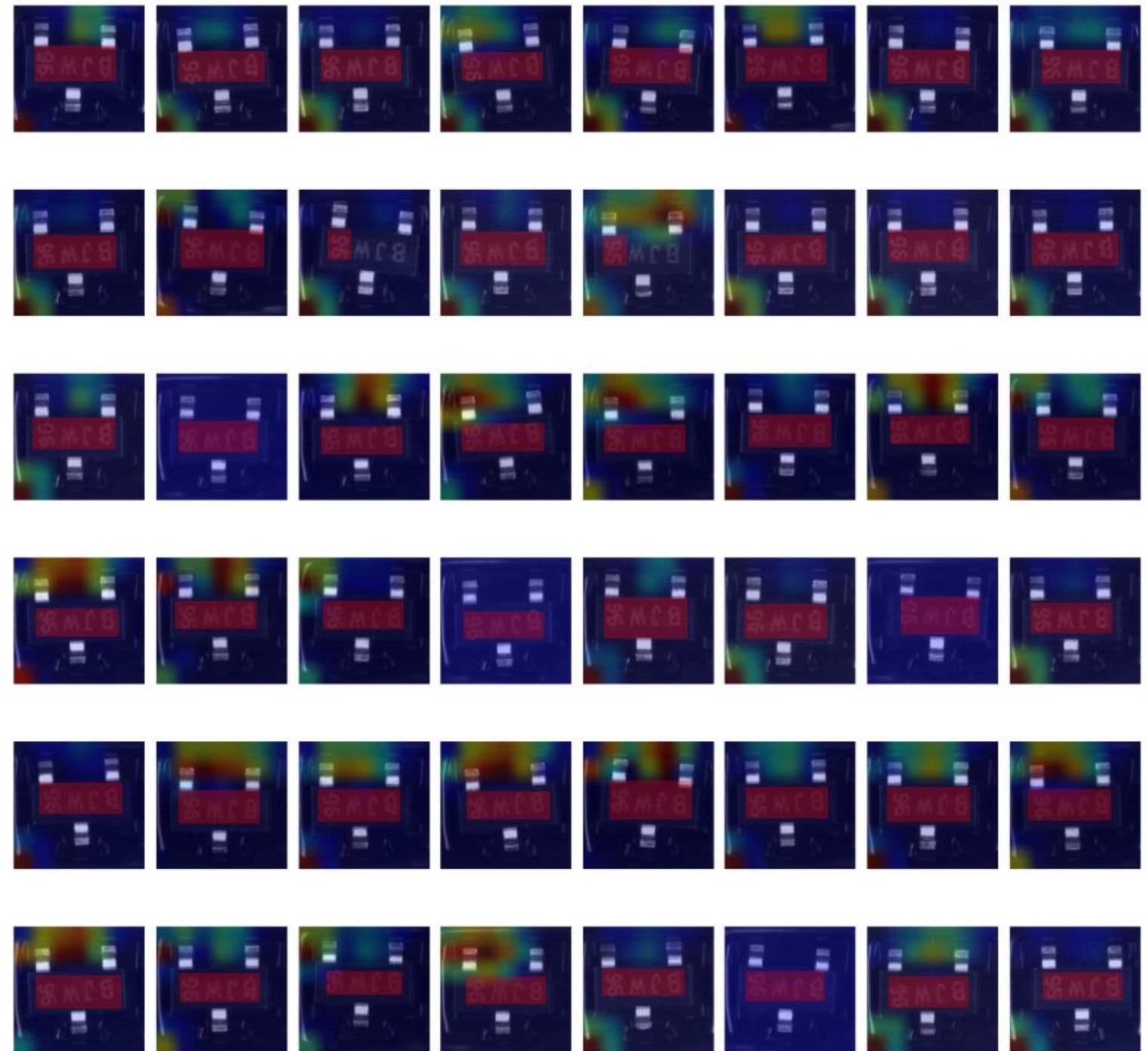


Better?

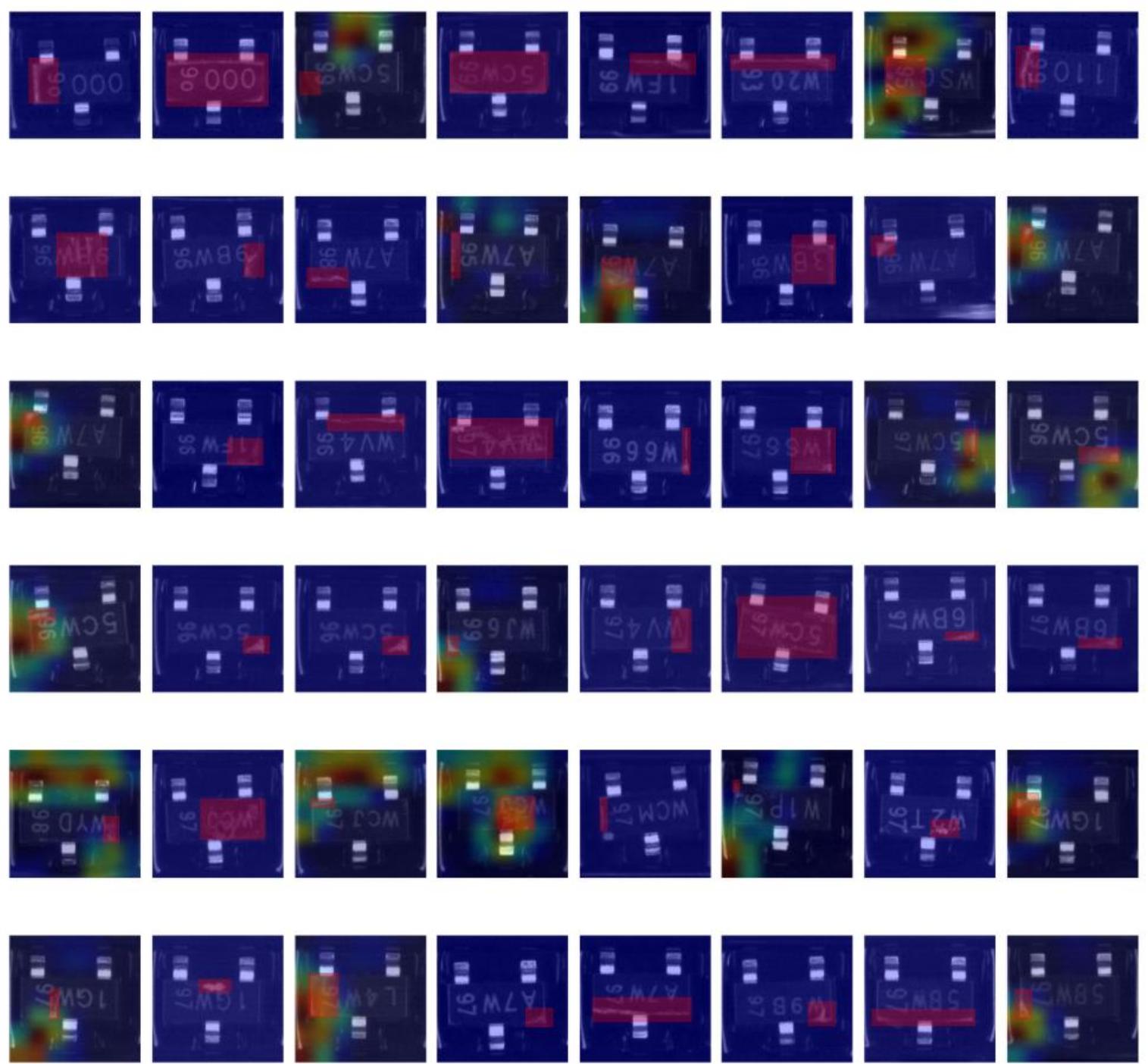
- ü Not highlighting the boundary!



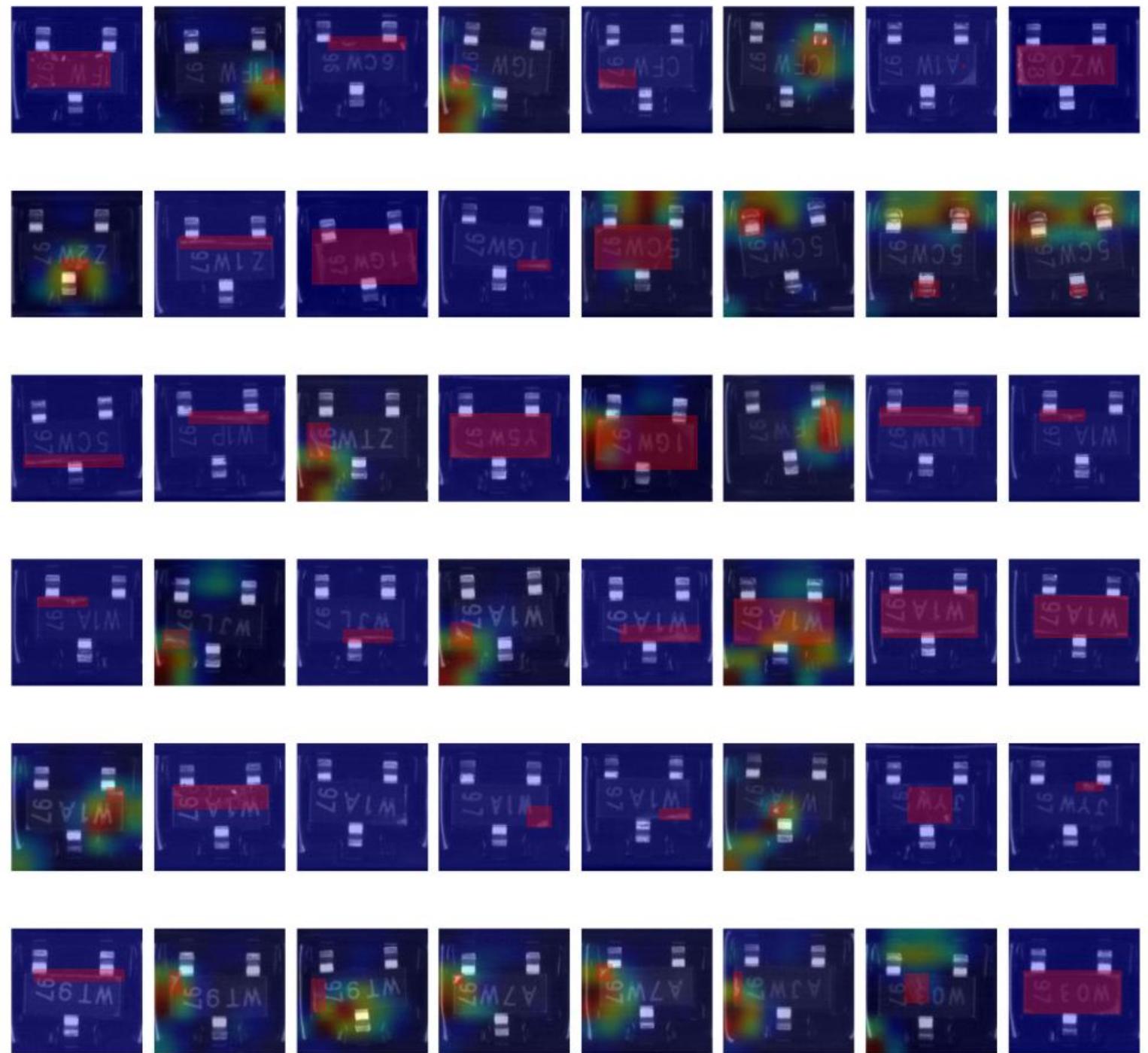
HeatMap



HeatMap

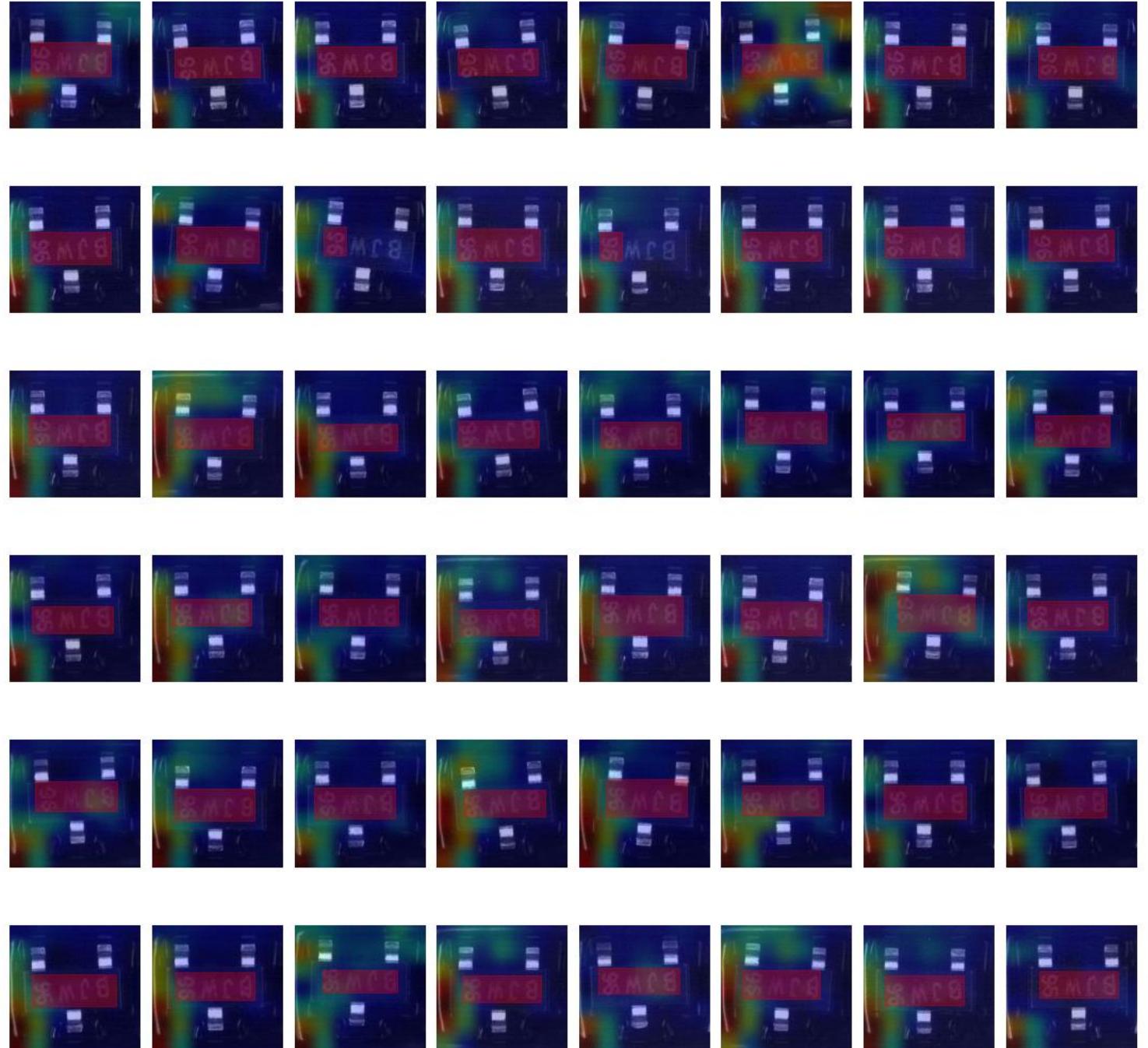


HeatMap

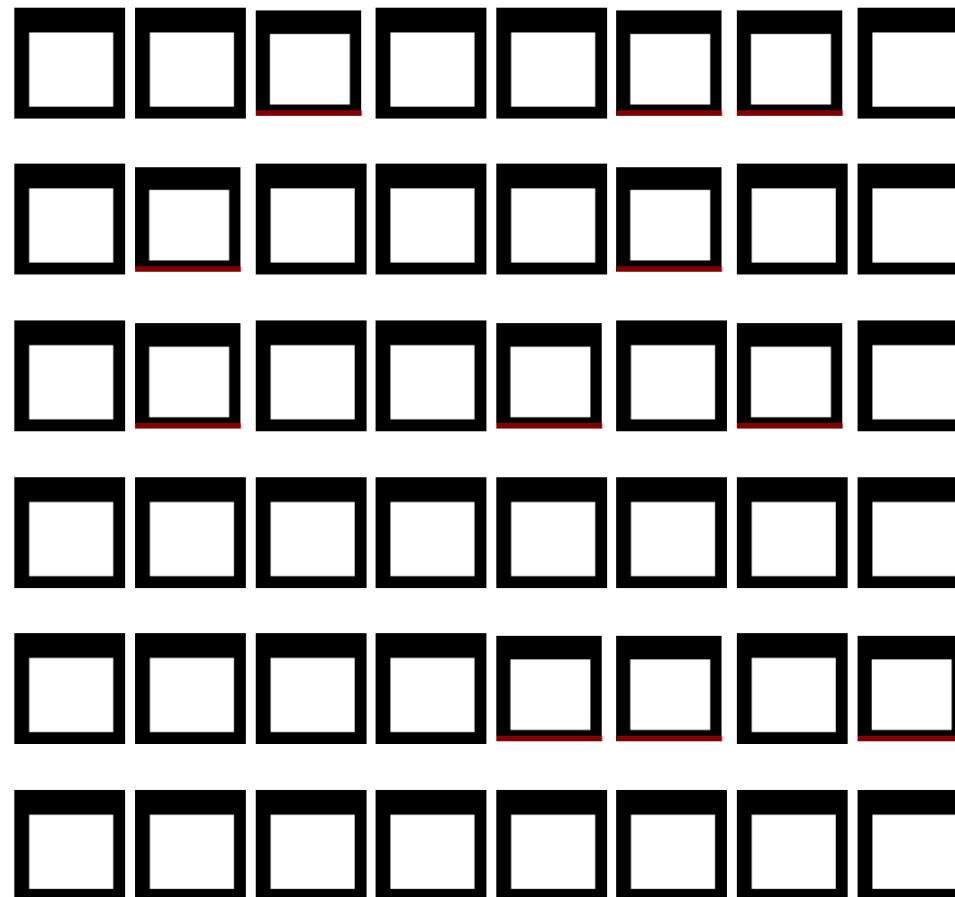


Is it Good or Bad?

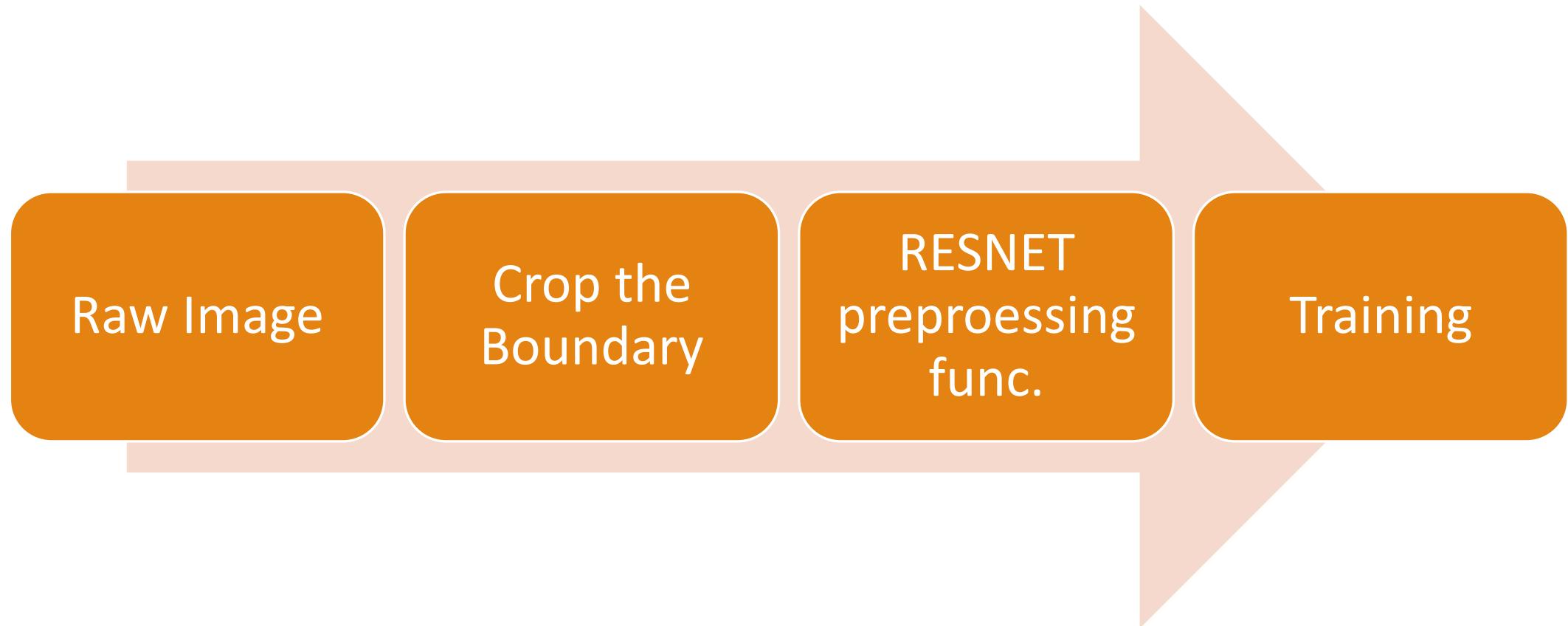
- ✓ High AUC! 0.98
- ✓ Wrong defect Area???



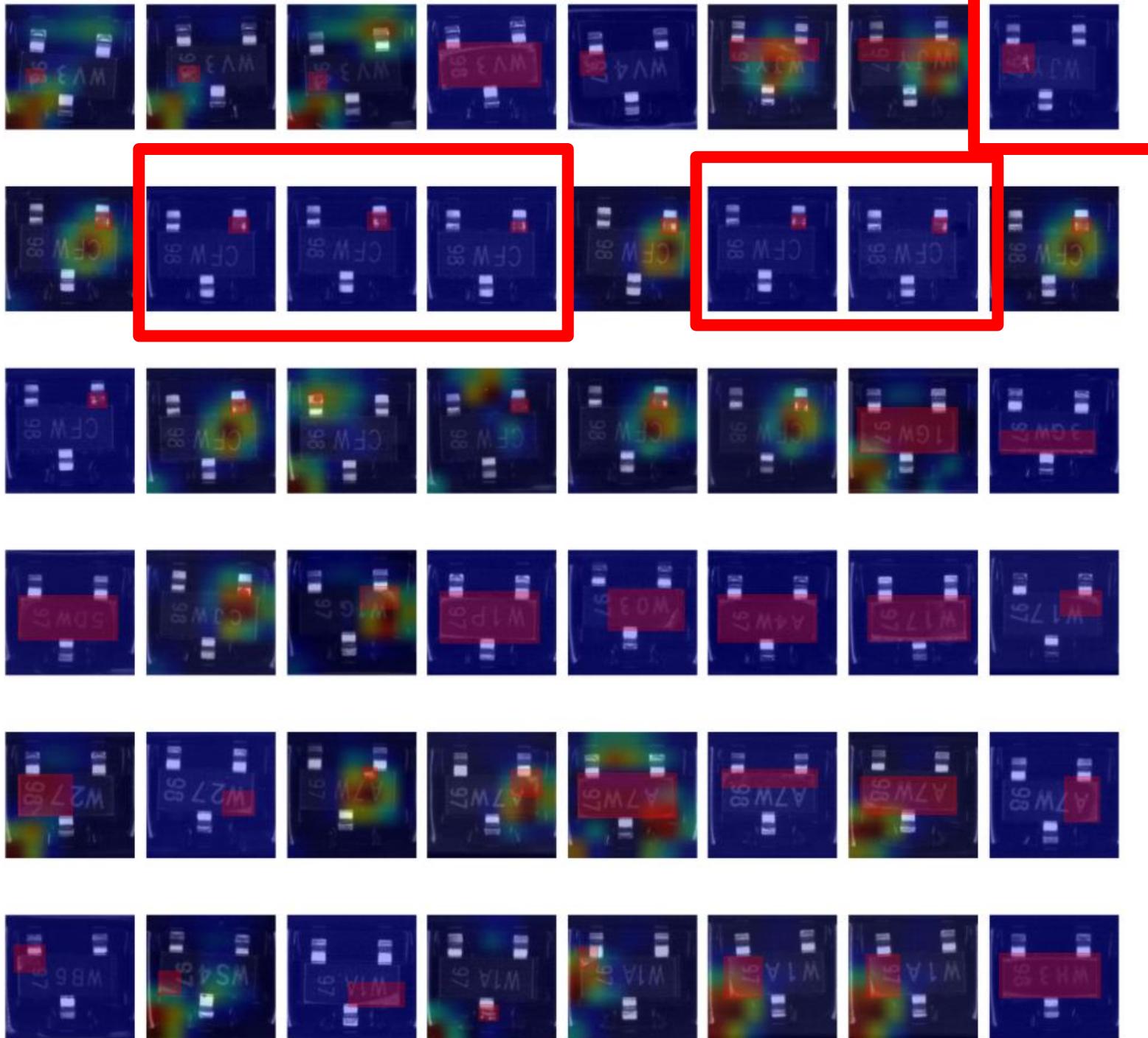
Crop the black part...



Flow



HeatMap



How to improve?

- ✓ Take a **better** picture!!! (some are Reflective!)
- ✓ Do some good pre-processing on the image!
- ✓ Early Stopping can always achieve higher AUC in the test data.
- ✓ Use all the training data (combine the training and validation set) for the prediction can always boost the score (Larger training data)
- ✓ Dropout may useful

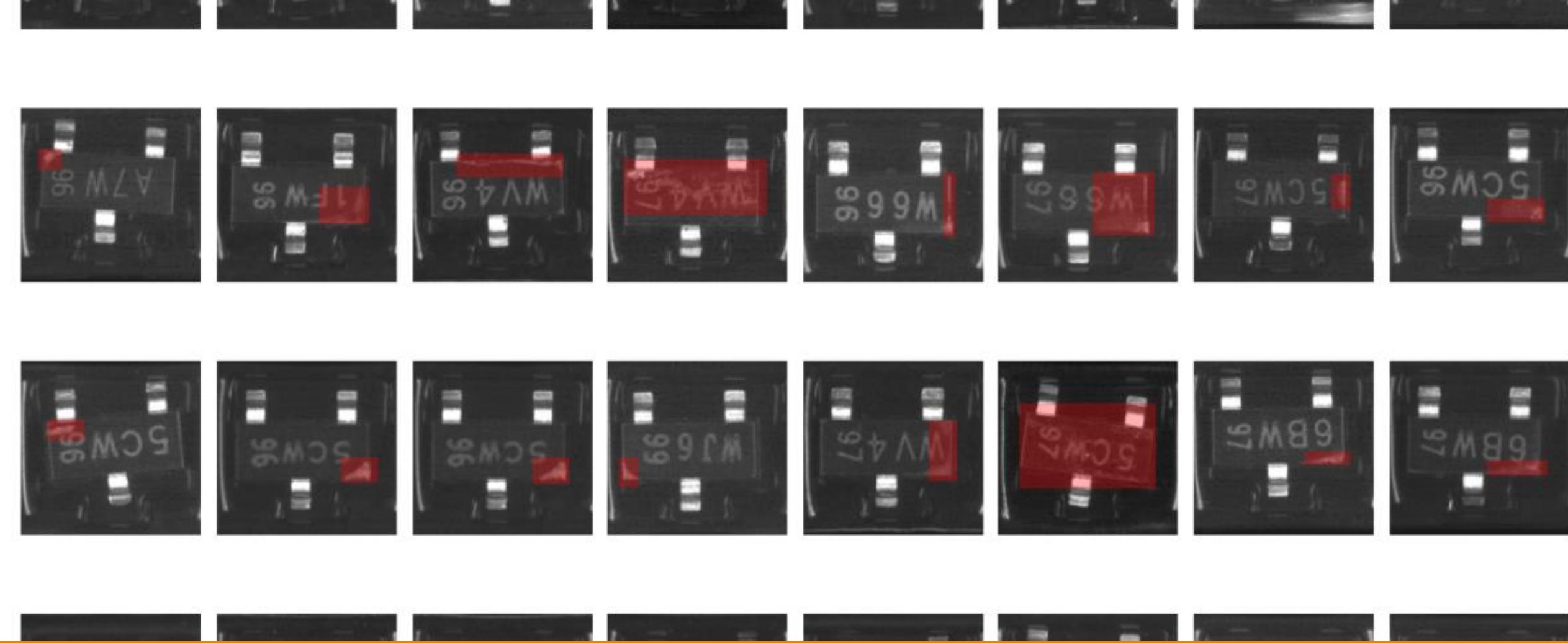
Training Data...



How to make use of this??

How to make good use of the defect area?

	id	x_1	y_1	x_2	y_2	width	height
0	SOT23DUMMY01_04-APG_ITIS_H52_1_111_4	40	100	99	198	59	98
1	SOT23DUMMY01_09-APG_ITIS_H52_1_12_3	28	90	242	204	214	114
2	WEA938001D1A_17-APG_ITIS_H49_1_40_2	10	131	52	179	42	48
3	WEA938001D1A_48-APG_ITIS_H51_2_203_1	25	86	229	175	204	89
4	WEE939001B0A_14-APG_ITIS_H20_1_374_4	106	90	242	134	136	44
...
6691	WEP93953252A_02-APG_ITIS_H53_2_340_4	39	166	191	197	152	31
6692	WEP93955394A_44-APG_ITIS_H52_2_360_1	25	107	241	195	216	88
6693	WEP93955452A_06-APG_ITIS_H51_1_230_4	151	87	226	117	75	30
6694	WEP93955514A_57-APG_ITIS_H54_2_138_2	172	147	227	171	55	24
6695	WEP94000313A_45-APG_ITIS_H45_1_368_1	75	88	216	230	141	142



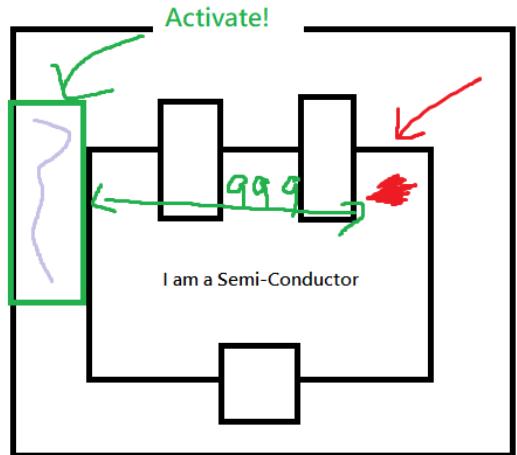
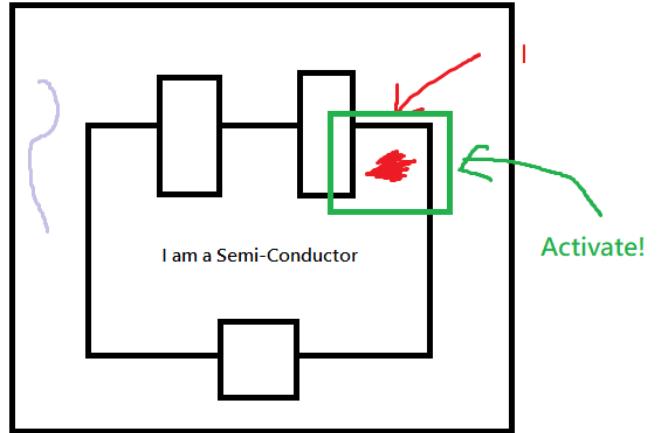
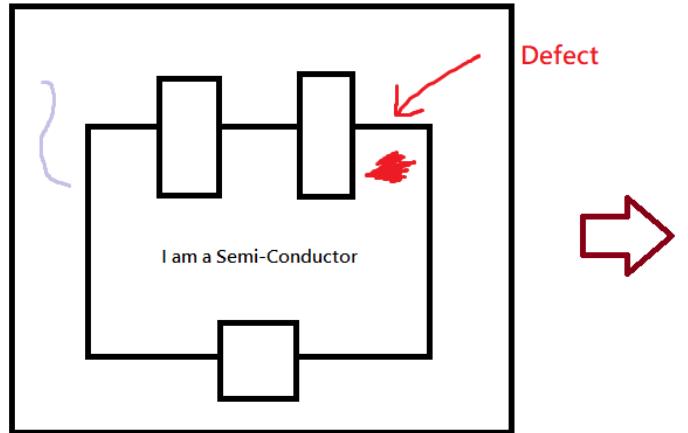
How to find out which region is defect?

Instead of just knowing is it defect.

Do it manually by human..?



Instead of AUC... New Metric?



Distance = 999
Predict: Defect!

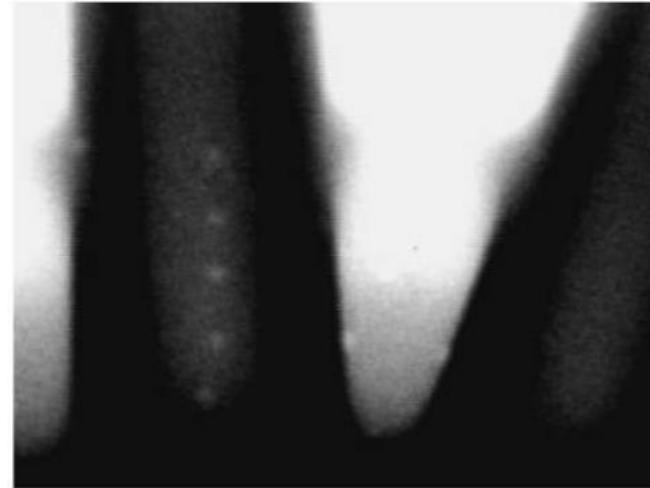
Distance = 0
Predict: Defect!

Draw in Windows/小畫家 :)

Some Idea..

Detection and Segmentation of Manufacturing Defects with Convolutional Neural Networks and Transfer Learning

<https://www.ncbi.nlm.nih.gov/pmc/articles/PMC6512995/>



Original Image

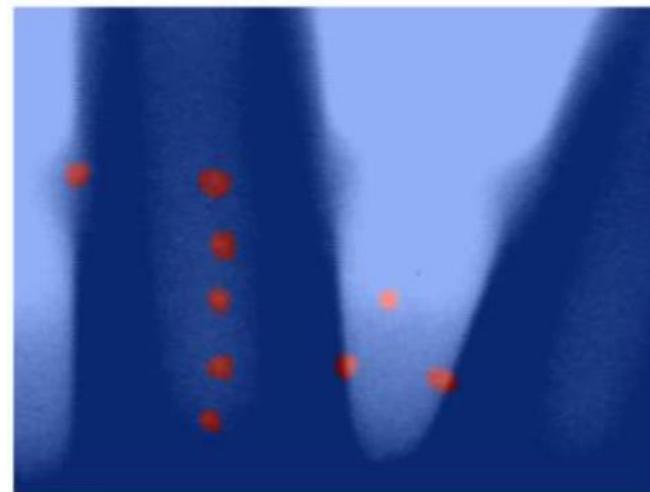
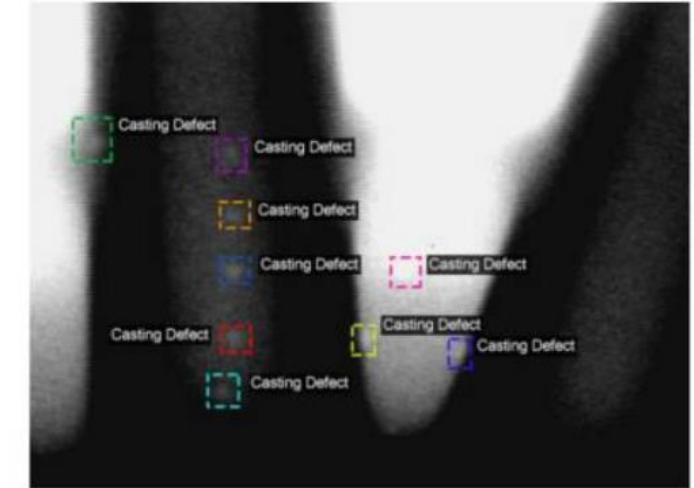
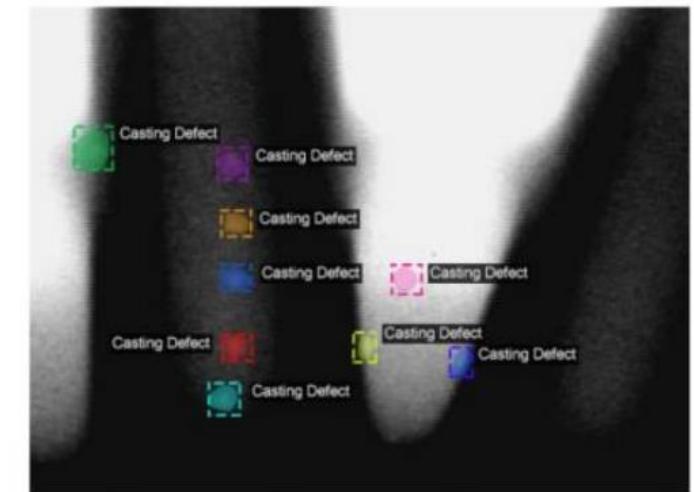


Image Segmentation



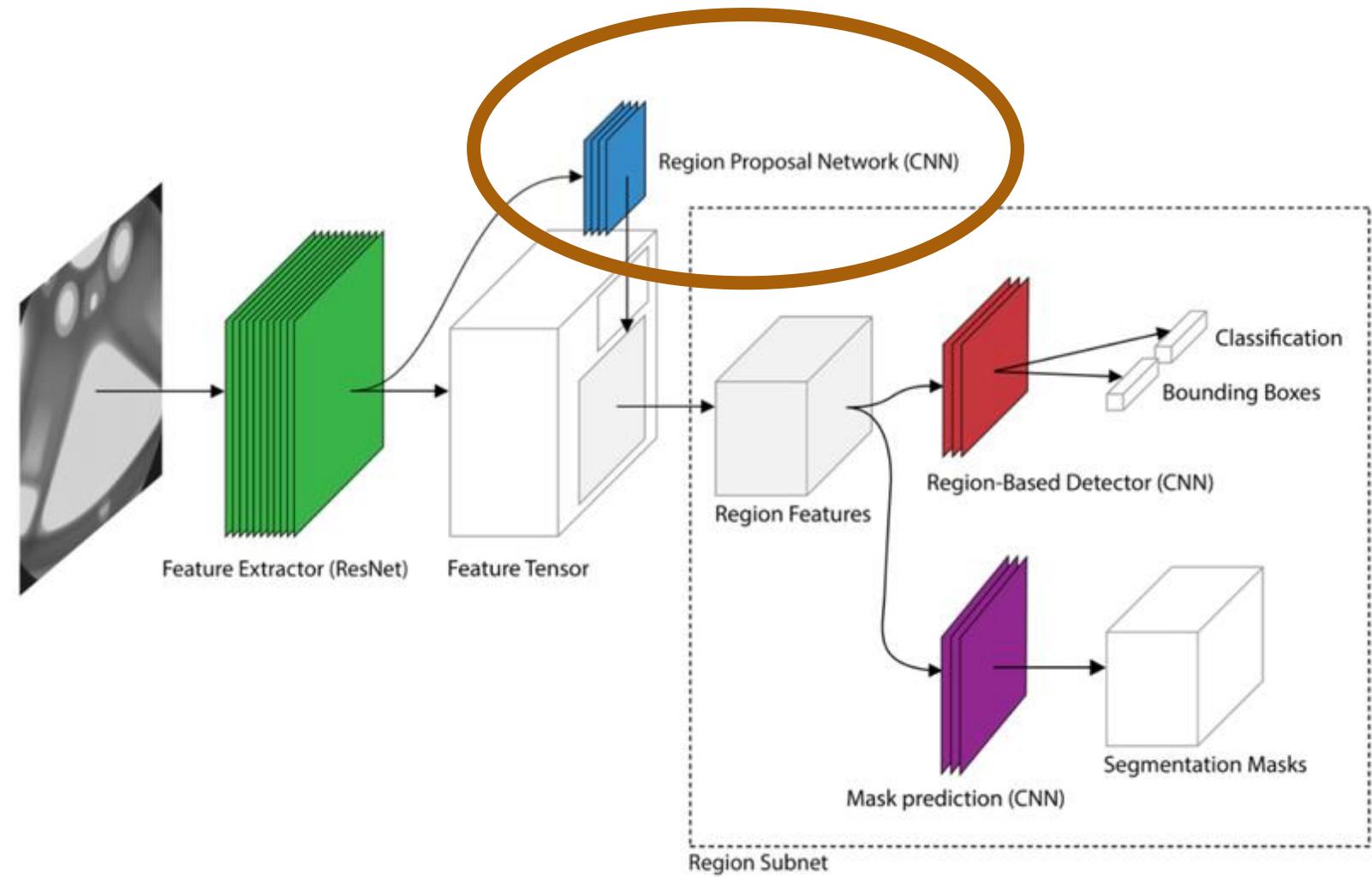
Object Detection



Instance Segmentation

Defect Detection System

The neural network architecture of the proposed defect detection system. The system consists of four convolutional neural networks, namely the ResNet-101 feature extractor, region proposal network, region-based detector and the mask prediction network.



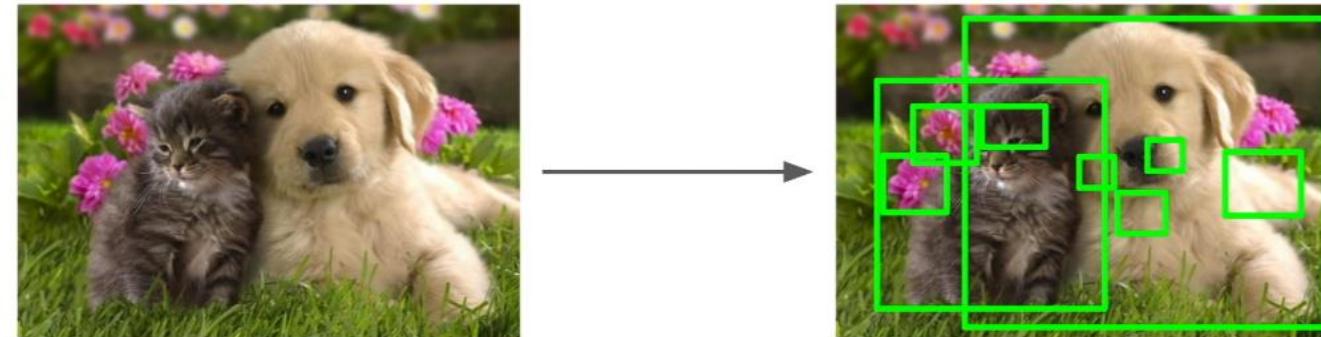
Region Proposal R-CNN

The region proposal is to find out the possible locations of the target in the figure in advance, which can ensure that the **higher recall rate** is maintained when fewer windows are selected.

And the obtained candidate window has higher quality than the typical **Sliding Window Algorithm**.

Region Proposals

- Find “blobby” image regions that are likely to contain objects
- Relatively fast to run; e.g. Selective Search gives 1000 region proposals in a few seconds on CPU



Do segmentation on the image | Problem: Slow

R-CNN:

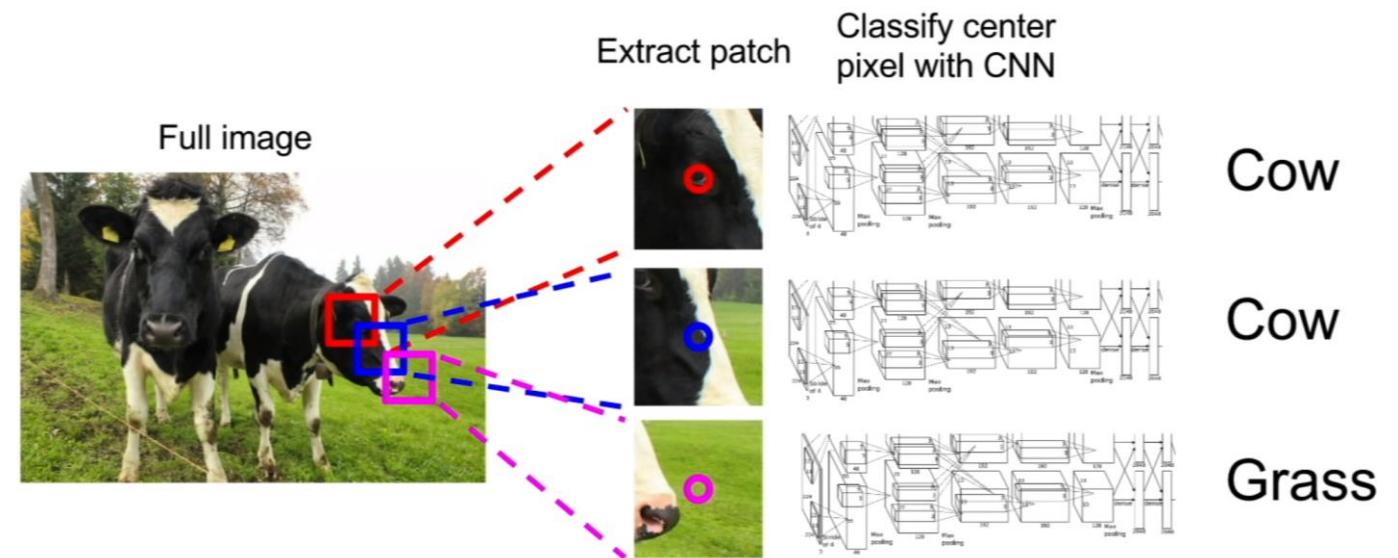
Propose regions. Classify proposed regions one at a time. Output label + bounding box.

<https://www.youtube.com/watch?v=6ykvU9Wulws&app=desktop>

<https://medium.com/@nabil.madali/demystifying-region-proposal-network-rpn-faa5a8fb8fce>

Sliding Window..

Semantic Segmentation Idea: Sliding Window

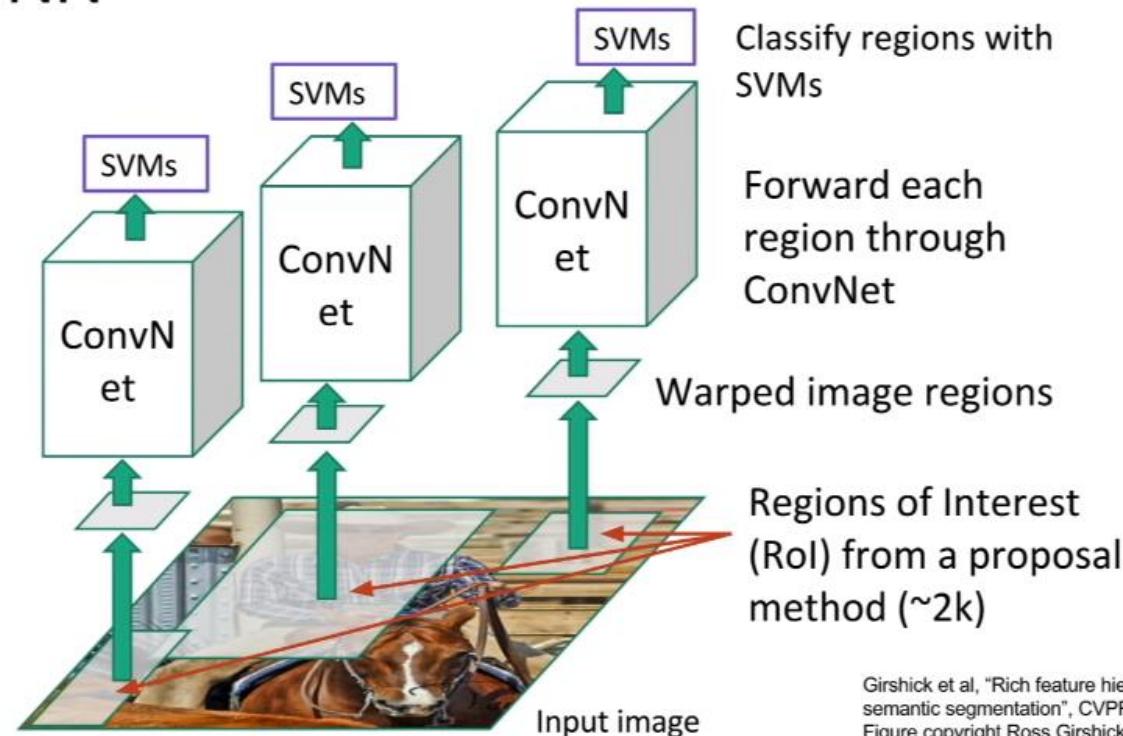


Region Proposal R-CNN

The region proposal is to find out the possible locations of the target in the figure in advance, which can ensure that the **higher recall rate** is maintained when fewer windows are selected.

And the obtained candidate window has higher quality than the typical **Sliding Window Algorithm**.

R-CNN



Girshick et al, "Rich feature hierarchies for accurate object detection and semantic segmentation", CVPR 2014.
Figure copyright Ross Girshick, 2015; [https://ur.ac.jp](#) Reproduced with permission.

<https://www.youtube.com/watch?v=nDPWywWRlRo>

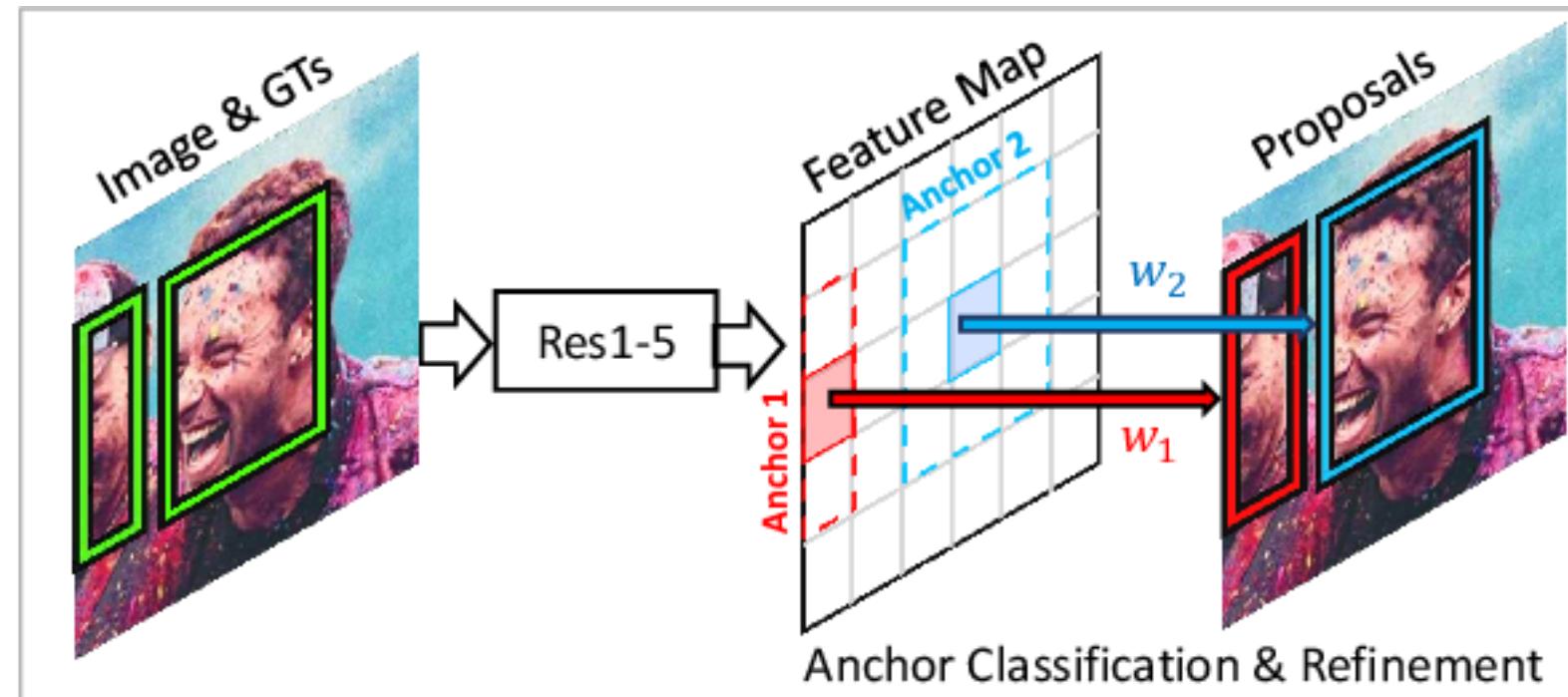
<https://www.youtube.com/watch?v=6ykvU9Wulws&app=desktop>

<https://medium.com/@nabil.madali/demystifying-region-proposal-network-rpn-faa5a8fb8fce>

Region Proposal Network

Suppose a picture is input, and after a series of convolution and pooling in the backbone network, a feature map of size $M \times N$ is obtained, which corresponds to dividing the original image into $M \times N$ areas.

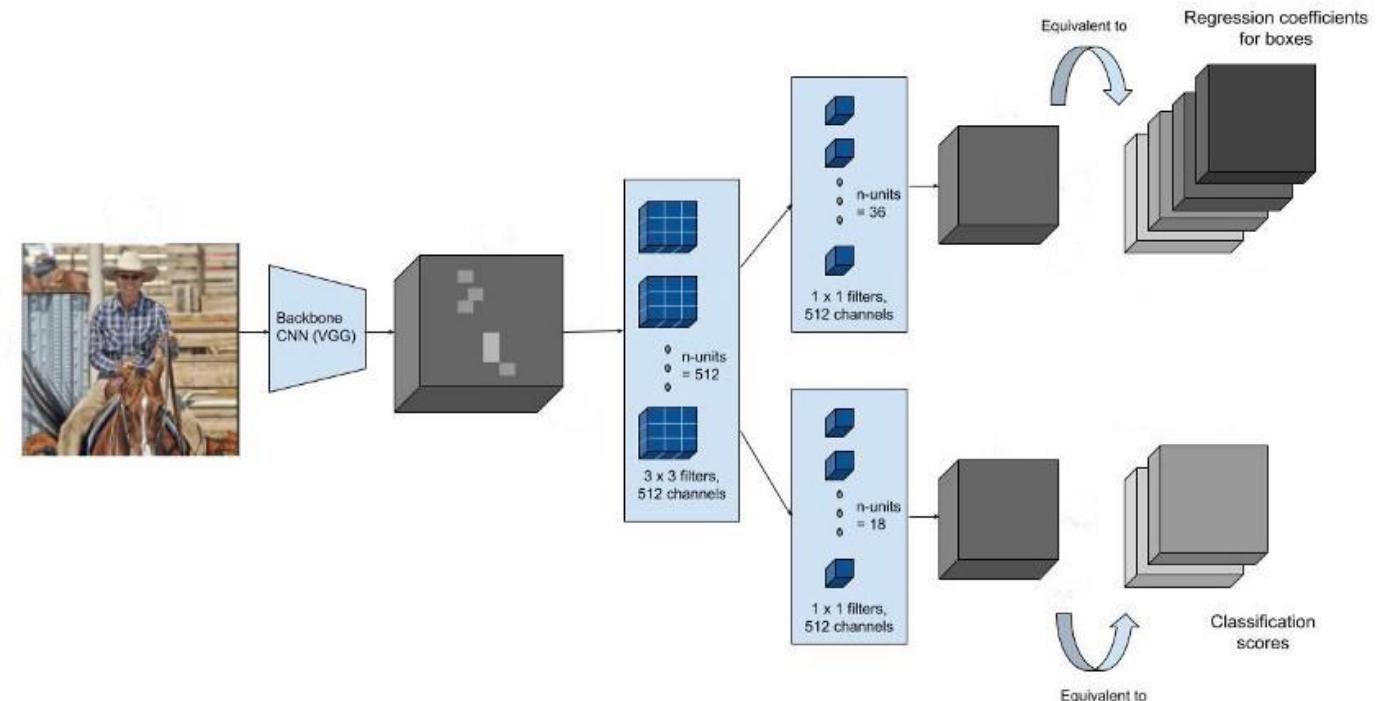
The center of each area of the original image is represented by the coordinates of a pixel on this feature map.



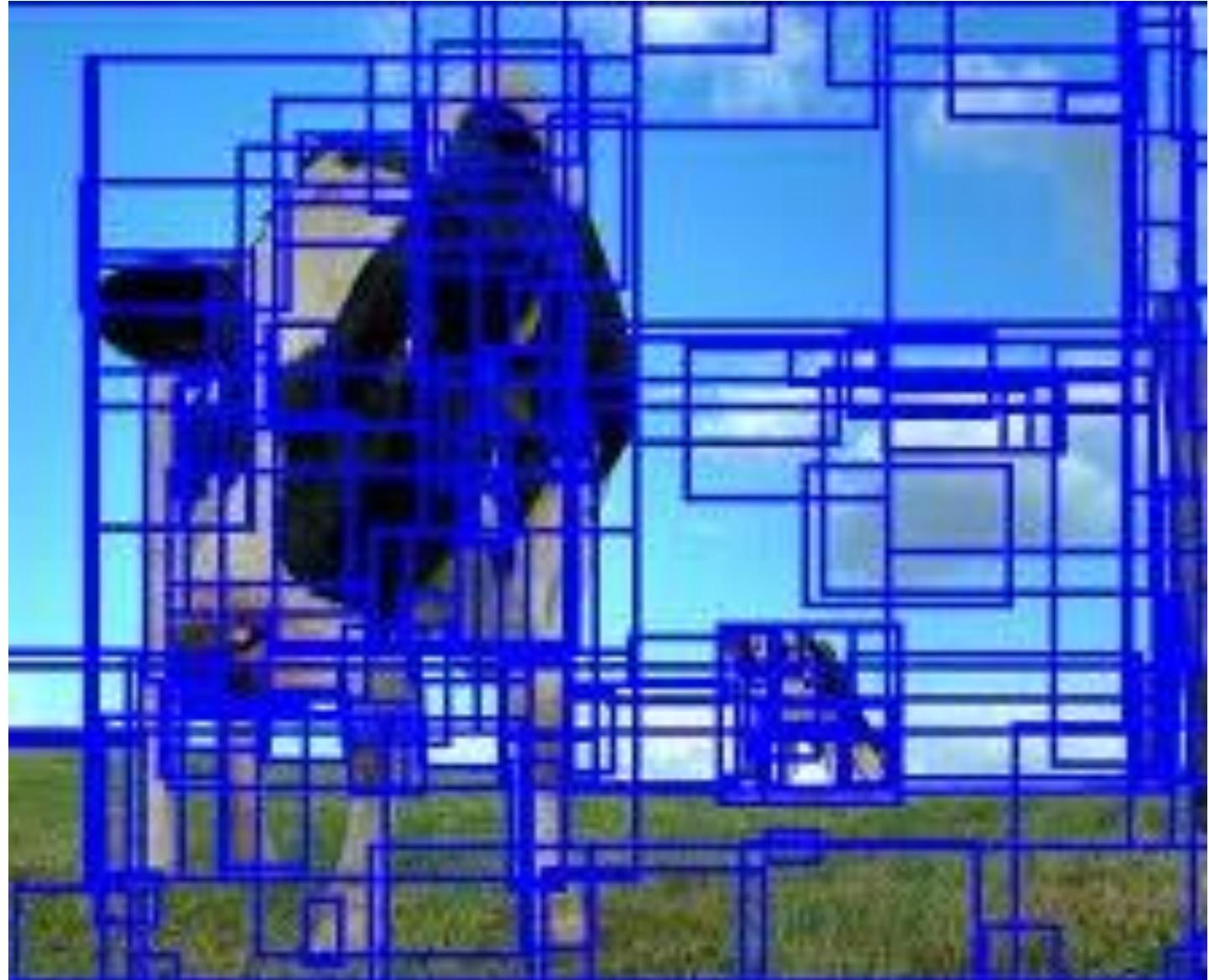
Region Proposal Network

RPN is used to determine whether the **k anchor boxes corresponding to each pixel contain a target.**

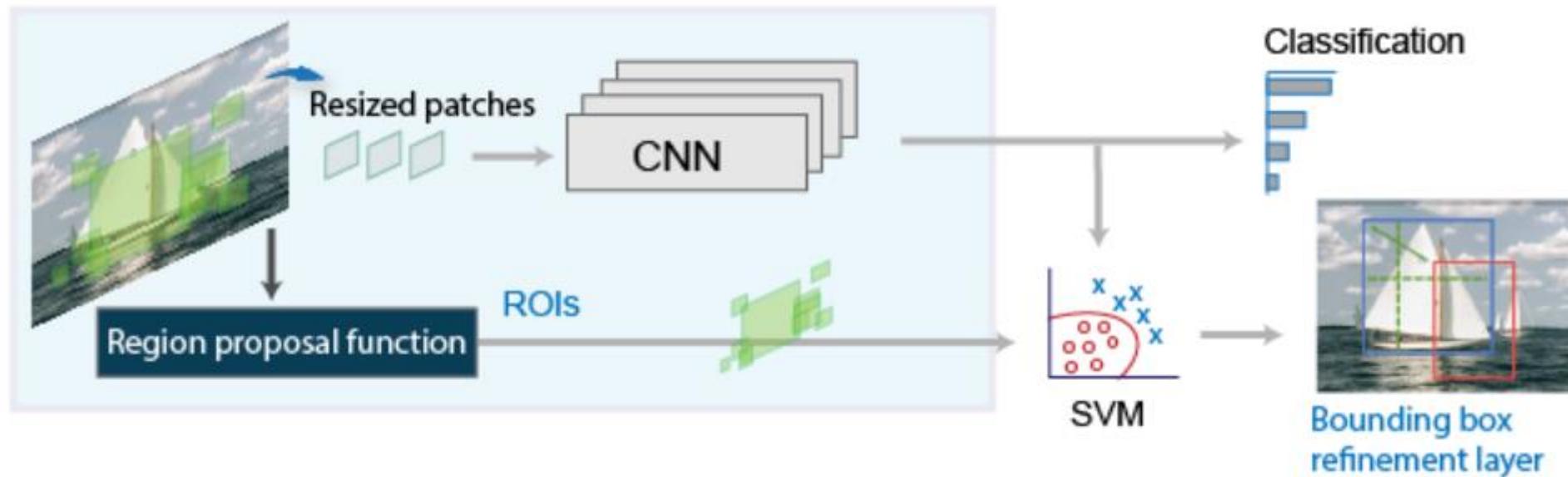
RPN layer must learn to classify the anchor boxes as background or foreground, and calculate regression coefficients to modify the position, width, and height of the foreground anchor box .



Examples Of RPN outputs



Getting Started with R-CNN, Fast R-CNN, and Faster R-CNN with MATLAB



<https://ch.mathworks.com/help/vision/ug/getting-started-with-r-cnn-fast-r-cnn-and-faster-r-cnn.html>

```
License checkout failed.  
License Manager Error -101  
All licenses are reserved for others.  
The system administrator has reserved all the licenses for others.  
Reservations are made in the options file.
```

Troubleshoot this issue by visiting:
<https://www.mathworks.com/support/lme/R2020a/101>

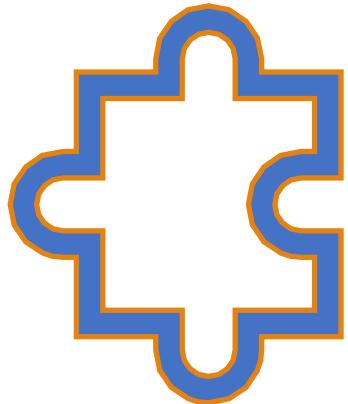
Diagnostic Information:

Feature: Video_and_Image_Blockset

License path: C:\Users\wkwongaw\AppData\Roaming\MathWorks\MATLAB\R2020a_licenses;C:\Program Files\MATLAB\R2020a\licenses\license.dat;C:\Program Files\MATLAB\R2020a\licenses\network.lic

Licensing error: -101,147.

No License for me to use some function in MATLAB ...



I can't implement
it :((((((

Not enough time... :(still want to try though



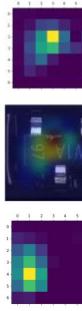
End of Semester:)

Nexperia Image Classification II with Deep Learning

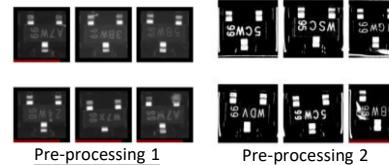
1. Introduction

Nexperia provided a dataset for Kaggle in-class contest that aims to classify images of semiconductor devices into two main classes, good and defect. We have created a simple CNN model and apply transfer learning with pre-trained RESNET50, VGG model. We either fine-tuning or just train the top layer in these model to predict the result. We will evaluate the performance of pre-processing technique and model with both the AUC score and the corresponding activation heatmap (Grad-CAM). We put more focus on the heatmap to see if the model can correctly identify the defect area stated in the dataset, then we will analyze the reason behind and propose a method of future improvement.

(The graph on the right shows which area are defected by visualize the gradient in the conv layer.)



In Method 2, we will apply a filter that when the intensity higher than a specific threshold, those pixel will be set to 1, otherwise, set it to 0.



It can highlight the "scratched" part in the image, however, it may also highlight the "noise" that negatively affect the prediction.

4. Experiment

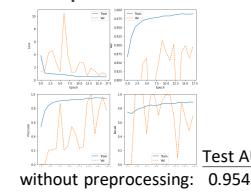
We first build a simple CNN model to train the data first, then use transfer learning to see if there is an improvement compared with our own mini-CNN model. To prevent overfitting, we have applied all the technique that may help to prevent such as dropout, L2 regularization, early stopping, save the best model during the training.

After experiment, Early Stopping can always achieve higher AUC than keep training the model till the end in all the experiment. (i.e. 50 epoch). Dropout and L2 regularization do not significantly boost the AUC score, but the training curve will become much stable. Fitting the dataset into either one of the model can achieve very high AUC already, however, we want to analysis something more than that. Due to the restriction of Kaggle that can submit at most 5 prediction (Although I have already submitted ~35 prediction csv file), we may not always evaluate the performance of different method with the test dataset.



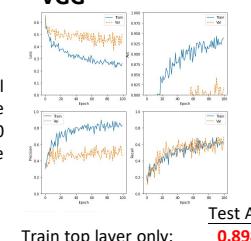
5. Main Result

Simple CNN



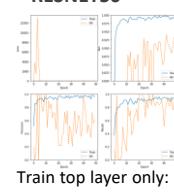
without preprocessing: 0.95439
with Pre-processing I: **0.97593**
with Pre-processing II: **0.75462**
(Always predict negative)

VGG



Train top layer only: **0.89869**

RESNET50



Train top layer only: 0.88462
Fine Tune whole Model (80% training set only): 0.986
Fine Tune whole Model (100% training set): **0.99157**

Notes: In most of the case, we just train the model with 80% of the training data for the test prediction only. The actual AUC after using the whole training data will be much higher after we have found the best method. Using the whole training set and usually boost 0.01-0.02 AUC.

5. Analysis

When the model always predict "Negative", the AUC will be 0.7, and the accuracy will be 0.75. A good model should be far higher than the above number, especially in the "Precision". Pre-processing II (Turning the image into black and white) have a negative impact in classification and the model always predict "Negative" in the method. Transfer learning can always give a better AUC compared to a simple model. The pre-trained weight and the very deep network in RESNET50 can help to identify important feature.

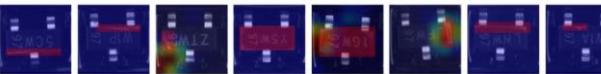
The alphabet in the middle of the semi-conductor does not affect the prediction, which is different as what I expected before doing it. We can see that there is no color on the alphabet in the heatmap. When the image pass-through the pre-processing function of RESNET50, the intensity of the character will become very small, or almost disappear.



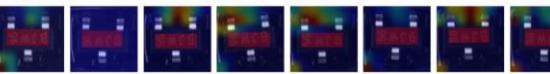
(Visualization of RESNET50 pre-processing function)

However, the boundary are activated and misclassify as defect in the heatmap on the right. The scratch on the boundary has misled the model when we do not crop the boundary in the image. We can see that RESNET50 pre-processing function will highlight the boundary part, and we think that cropping the boundary should increase the AUC score significantly. In the simple CNN model, the cropping help to get a better AUC (from 0.95 to 0.97), but in the pre-trained model, cropping will drop the AUC from 0.99 to 0.983. Although the model predict the sample as "defect" due to the boundary and the actual label are also "defect", cropping the boundary will lead to a lower confidence of predicting the sample as "defect".

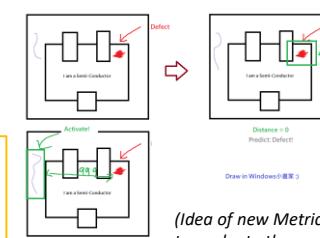
Moreover, we have observed several defect type: straight line, corner, whole conductor, metal or empty. The model can easily identify the defect in the corner of the conductor, however, it is very hard to detect a straight-line type. There is few / no activation on the straight-line scratch in the graph below.



Although the model successfully classify the image as "defect", but if we look at the heatmap, the activation is quite different with the defect area given in the dataset. During the training, we do supervised learning with the correct "label" only, but we didn't tell the machine that which areas are defected. The model have to find out the area by itself through back-propagation, and there are many "noise" in the semi-conductor in each image, causing this kind of activation. The importance of data cleaning which try to make the image as clean as possible like removing the unnecessary boundary scratch should help the prediction process. In this dataset, most of the noise are in the boundary, and we should crop it out for better training. Although the AUC decrease, the activation heatmap will be closer to the given defect area.



If we want to evaluate how good the model in predicting the defect area, we may define a new metric as the distance between the defect location given in the dataset and the predicted defect location. Here, the predicted defect location will be the most activated location in the heatmap.



Idea of new Metric to evaluate the goodness of finding the defect area

6. Possible Future Work for Improvement

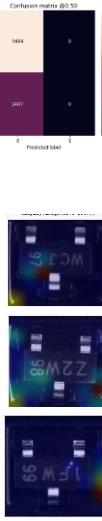
Although our current method can give us a brief idea of where is the defect area in the semi-conductor, we want to make good use of the defect area file and want to better supervise the model to identify the defect area, instead of finding it by itself so as to increase the power of prediction. After some research, it seems that the idea of Region Proposal CNN may help us achieve it. Below is a small abstract of this model.

R-CNN

The region proposal is to find out the possible locations of the target in the figure in advance, which can ensure that the higher recall rate is maintained when fewer windows are selected. And the obtained candidate window has higher quality than the typical Sliding Window Algorithm .

Source: <https://medium.com/@nabil.madali/demystifying-region-proposal-network-rpn-faa5a8fb8fce>

ID	SOIT2305MMH01_14-APO-JTB_H52_1,11,4	X_1	X_2	X_3	width	height
0	SOIT2305MMH01_14-APO-JTB_H52_1,11,4	40	100	99	198	98
1	SOIT2305MMH01_14-APO-JTB_H52_1,1,12	26	90	242	204	114
2	WEA9300101_APO-JTB_H52_1,1,13	25	98	241	204	100
3	WEA9300101_APO-JTB_H52_1,2,20,3	25	98	226	175	204
4	WE89300101_APO-JTB_H52_1,3,7,4,4	108	90	242	135	44
4991	WEP93051323_02-APO-JTB_H52_1,3,4,4	39	169	191	197	152
4992	WEP93051324_44-APO-JTB_H52_2,26,0,1	29	107	241	195	216
4993	WEP93051424_44-APO-JTB_H52_1,2,20,3	25	98	226	175	30
4994	WEP93051514_57-APO-JTB_H52_1,2,18,2	172	147	227	171	55
4995	WEP94000314_49-APO-JTB_H52_1,1,11	75	58	216	230	141



There are quite a number of paper in the US use this method with transfer learning to find out the manufacturing defect . We attempt to implement this model in MATLAB and Pytorch but we still need more time. Let's try my best later in the coming holiday :)